Second Annual Progress Report:

## DESIGN AND APPLICATION OF ELECTROMECHANICAL ACTUATORS FOR DEEP SPACE MISSIONS

Submitted to:
NASA
Marshall Space Flight Center EP64

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The University of Alabama
College of Engineering

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## Submitted to:

NASA
Marshall Space Flight Center EP64
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## I. EXECUTIVE SUMMARY

This progress report documents research and development efforts performed from August 16, 1993 through August 15, 1994 on NASA Grant NAG8-240, "Design and Application of Electromechanical Actuators for Deep Space Missions." Since the submission of our last progress report in February 1994, our efforts have been almost entirely focused on final construction of the test stand and experiment design. Hence, this report is dedicated solely to these topics. However, updates on our research personnel and our health monitoring and fault management efforts are provided in this summary.

Following this executive summary, are two report sections. The first is devoted to the motor drive being constructed for the test stand. The thrust of the next section is the mechanical and hydraulic design and construction based on the planned experimental requirements. Following both major sections are three appendices.

## I.1. Research Personnel

Since the beginning of this project, two faculty members, seven graduate students, and four undergraduate students have been involved. These individuals are listed below:

1) Tim A. Haskew*, Project Director, Co-Principal Investigator
2) John Wander*, Co-Principal Investigator
3) Kris Cozart*, M.S. Student, Mechanical Engineering
4) Sumit Bhattacharyya, M.S. Student, Electrical Engineering
5) Ramomohan Challa ${ }^{+}$, M.S. Student, Computer Science
6) Stuart Payne, M.S. Student, Mechanical Engineering
7) Thomas Salem*+, Ph.D. Student, Electrical Engineering
8) Yoon Gyeoung Sung, Ph.D. Student, Mechanical Engineering
9) Stanley McCarter, B.S. Student, Electrical Engineering
10) Sean McGraw, B.S. Student, Electrical Engineering
motor and drive used on the test stand. A data sheet for the ADSP-21020 is provided in Appendix A.


Figure II.1. Block Diagram of Electrical System.

The resolver electronics selected are manufactured by Data Device Corporation. An OSC-15801 reference oscillator and power amplifier and an RDC-19220 resolver to digital converter were purchased. The output from the RDC is a 12 bit word that is the natural binary angular position of the shaft. Additionally, an analog velocity output and a binary direction bit are available. The 12 bit word output serves as input to the commutation circuitry.

## II.1. Commutation Circuitry

In order to provide the necessary electronic commutation, a digital logic circuit was designed to provide the IGBT gate control signals. In order to be able to accurately model drive behavior in applications where hall effect sensors are used for commutation sensing, three comparator circuits were constructed to convert the 12 bit binary angle
representation to the equivalent hall effect signals. The outputs from the three comparators are the Hall A, Hall B, and Hall C outputs.

When hall effect sensors are utilized, there binary outputs are a function of the angular position of the machine rotor. This is illustrated in Figure II.2.


Figure II.2. Hall Effect Signals.

The purpose of the Hall effect generators is to convert the natural binary angle to a one digital bit representative of Figure II.2. This was accomplished using dual twelve bit comparators for each hall signal.

If we define the turn-on angle as $\theta$ and the turn-off angle as $\phi$ for any one of the three Hall signals, then two binary variables, $X$ and $Y$, can be defined as in (II.1) and (II.2).

$$
\begin{align*}
& X=\left\{\begin{array}{l}
0 \text { if angle }<\theta \\
1 \text { if angle } \geq \theta
\end{array}\right. \\
& Y=\left\{\begin{array}{l}
0 \text { if angle }>\phi \\
1 \text { if angle } \leq \phi
\end{array}\right. \tag{II.1}
\end{align*}
$$

These two binary variables are generated by 2 sets of 3 cascaded 4-bit magnitude comparators. The angles against which the actual rotor angle is compared is dip-switch programmable. The Hall signals can be produced from X and Y through combinational
logic. The logic is identical for Hall $A$ and $C$, and can be seen from Schematic 2. Schematic 2 is drawn for Hall A, and the only difference for Hall C is the dip-switch setting. However, for Hall B, the logic differs slightly due to the fact that the on-time for Hall B spans the zero degree crossing. The Hall B circuit is provided in Schematic 3.

With equivalent hall effect signals, the generation of digital representations of the six gate signals for the IGBTs is accomplished using a decoder and combinatorial logic as designed by Nelms [II.1]. The decoding for Nelms work was accomplished using CMOS technology, but we have employed a TTL equivalent. One additional difference can be noted from the work in [II.1]. Nelms redefines the positive sense of angular measurement of the rotor position depending on the direction of rotation. We have chosen to maintain a constant positive sense of angular position regardless of rotational direction. Thus, in order to alter the IGBT firing sequence for the reverse direction, a forward/reverse ( $\mathrm{F} / \mathrm{R}$ ) bit is required on the extra input to the decoder. This circuit is provided in Schematic 4.

Also shown in Schematic 4 is the logic for including the PWM switching. The three lower-leg IGBTs switching signals are and a PWM signal are combined through an and operation. While the commutation logic requires that a lower leg IGBT be conducting, it will only be allowed to conduct if the PWM signal is high. The output of the and gates performing this function are then buffered with open-collector inverting buffers. These six buffered gate signals, one for each IGBT, supply input to the IGBT gate drives. The selected gate drive topology is identical to that employed in [II.1]. The gate drive circuit is shown in Schematic 5. For isolated switching of the IGBT gates, four independent and isolated power supplies are required. These power supplies are Power/Mate Corporation SU-UNI-30EV regulated units.

## II.2. PI Speed Controller

The PC that will be used for data acquisition and control will be responsible for all upper-level control functions associated with the electrical subsystem of the test stand. While monitoring the LVDT for roller screw nut position, it will provide an analog speed command to the motor drive. This command will be buffered, and the actual speed signal from the RDC-19220 will be subtracted. This error will be operated on by two LF351 op-amps to provide proportional and integral signals, which will be added. This output will be proportional to the reference motor current. This section of the controller will be virtually identical to that prototyped in [II.1].

With a given reference current and a signal proportional to the dc input current, a current error signal can be generated with an LF351 operational amplifier in a unity gain differencing configuration. This current error will be provided as input to the PWM logic. Note here that the current being regulated is the dc input current, not each phase current. Since only two IGBTs will be conducting at any time, this is an acceptable alternative to regulating all three phase currents. The result is a net reduction in control electronics.

## II.3. PWM Logic

A triangular modulating wave will be generated using an LF351 operational amplifier circuit. The current error signal and the modulating wave will be compared using an LM311 analog voltage comparator. This comparison will provide the PWM gating signal that is required by the gating logic, and the LM311 will directly drive the TTL and gates.

## II.4. Present Status

At this point, all of the motor drive has been designed, and much has already been constructed. Figure II. 3 displays our initial block diagram of the system with shading used to indicated the present status of each component. The entire system is expected to be operational in early September 1994.


Figure II.3. Present Status of Electrical System.

## II.5. Further Efforts

When the electrical system is proven, we will begin development of the real-time health monitoring system using the Analog Devices DSP card described in the Executive

Summary. Additionally, we will explore a reduction of the discrete component digital circuitry that has been employed to a single programmable logic array.

With regard to control techniques, we hope to begin interfacing the health monitoring system to the controller within the feedback loop while injected noise into the actual feedback signals. Failed sensor experiments will be performed as well. These efforts will also initiate our work on using the health monitoring equipment for sensor reduction. Other researchers have developed techniques for sensorless control and commutation [II.2, II.3], and there methods will serve as the point of departure for our development.

## II.6. References

[II.1] Nelms, R. Mark, Final Report for Design of Power Electronics for TVC EMA Systems, Contract No. NASA-NAS8-39131, Delivery Order No. 12, August 30, 1993.
[II.2] Furuhashi, Takeshi, Somboon Sangwongwanich, and Shigeru Okuma, "A Position-and-Velocity Sensorless Control for Brushless DC Motors Using an Adaptive Sliding Mode Observer," IEEE Transactions on Industrial Electronics, vol. 39, no. 2, pp. 89-95, April 1992.
[II.3] Matsui, Nobuyuki and Masakane Shigyo, "Brushless dc Motor Control Without Position and Speed Sensors," IEEE Transactions on Industry Applications, vol. 28, no. 1, pp. 120-127, January/February 1992.

## III. DETAILED EXPERIMENT PLANNING

There are three basic experiment types that are planned for the very near future. One or these, the transverse loading experiment, is a relatively simple experiment with minimal requirements on the motions executed by the roller screw and with an expected negative result-- it is expected that the bearings will not fail under transverse loading. The motivation for this experiment has been somewhat diminished for two reasons. First, the prototype design being considered by NASA shields the roller screw from the bulk of any loading due to transverse acceleration of the actuator. Secondly, continued discussions with Pierre Lamore of SKF have clarified the general warning about transverse loads on the roller screw. In an earlier conversation with Pierre he said that the transverse loads should never exceed $10 \%$ of the actual axial load. After meeting with Pierre at the Prospector VI Conference on EMAs this spring, it became clear that the specification is that the transverse load should not exceed $10 \%$ of the rated axial load. It also became clear that this is a very loose rule of thumb suggested by SKF that is motivated by the concentrated loading that occurs on individual rollers when under transverse loading. A more appropriate specification would have to include information about the actual axial load and the number of rollers and the roller/nut geometry. Since SKF has not provided more specific design equation, it is suggested that a test be performed under the maximum axial and transverse loads anticipated with the expectation that the bearings will not fail catastrophically or be brinelled. If the same roller screw is to be used on repeated missions, the fatigue life of the bearings should be considered but this too should prove to be of little concern given the brief duty cycle of SSME TVC actuators.

The other two tests require more accurate force and/or displacement trajectories be executed during the test and so require an understanding of the governing dynamics of
the system under test. The tests to be performed are simulations of the startup and shutdown transient loadings and of the actual mission duty cycle. The dynamics equations that model these tests are developed below.

## III.1. General Modeling Equations for the Test Stand

There are three different rigid-body speeds involved in the TVC actuator and in the test stand envisioned to test the TVC actuator. There is the linear speed of the output side of the actuator, the rotational speed of the screw shaft, and the rotational speed of the motors that drive the screw. If there is a direct drive connection between the motors and the screw shaft, the number of speeds of interest reduces to two. Because all of these speeds are kinematically constrained with respect to each other, it is possible to refer the entire mass of the system to any of the motions associated with these speeds. At some times, for example for motor specification, it is most convenient to refer the entire mass of the system and any loss terms and loads to the rotational motion associated with motor revolutions. At other times, for example when determining the flow requirements placed on the hydraulic loading device that produces specified force/time inputs to the actuator nut, it is most convenient to refer all system elements to the linear motion. For both cases, direct application of energy or power conservation laws produces the servo like system descriptions represented by (III.1). The loading terms $\mathrm{T}_{\mathrm{m}}$ and $\mathrm{F}_{1}$ are the motor torque and linear actuator force as depicted in Figure III.1.


Figure III.1. Actuator Schematic.

$$
\begin{align*}
& \left(J_{m}+g^{2} J_{s}+\left(g P_{h}\right)^{2} M_{l}\right) \dot{\omega}_{m}+B \omega_{m}=\frac{2 \pi g P_{h} F_{l}}{\eta_{r}}+\eta_{g} T_{m}  \tag{III.1}\\
& \left(\frac{J_{m}}{\left(g P_{h}\right)^{2}}+\frac{J_{s}}{P_{h}^{2}}+M_{l}\right) \dot{V}_{l}+\frac{B}{\left(g P_{h}\right)^{2}} V_{l}=\frac{F_{l}}{\eta_{r}}+\frac{\eta_{g} T_{m}}{2 \pi g P_{h}}
\end{align*}
$$

where:
$\mathrm{J}_{\mathrm{m}} \quad$ is motor inertia,
g is gear reduction between motor and screw,
$\mathrm{J}_{\mathrm{S}}$ is screw inertia,
$\mathrm{P}_{\mathrm{h}} \quad$ is screw lead (linear/revolution),
$\mathrm{M}_{1} \quad$ is the mass of the actuator that moved linearly,
B is a visous loss term associated with the motor angular motion,
$\omega_{\mathrm{m}} \quad$ is the angular velocity of the motor,
$\mathrm{V}_{1}$ is the linear velocity of the load-end of the actuator,
$\mathrm{T}_{\mathrm{m}} \quad$ is the torque generated by the motor(s), and
$F_{1} \quad$ is the force applied to the end of the actuator.

These equations are complicated by the essentially nonlinear efficiency model of the energy losses associated with the transmission elements. The efficiency terms $\eta_{\mathrm{r}}$ and $\eta_{\mathrm{g}}$ in the equations below represent the efficiencies of the gear and roller screw transmissions assuming that energy flows into the actuator system at the motor and out of
of the system at the linear attachment point. In these equations, the $\eta$ terms will move between the numerator and the denominator as the direction of energy flow changes at the motor or the linear load. It is possible for any of the four possible combinations of energy flow, and hence $\eta$ term location, to occur. If a standard DC motor model is assumed while neglecting the motor inductance the motor torque $\mathrm{T}_{\mathrm{m}}$ can be replaced using the equation

$$
\begin{equation*}
T_{m}=K_{t}\left(V_{i n}-K_{b} \omega_{m}\right) / R_{a} \tag{III.2}
\end{equation*}
$$

Implementing this substitution, simple models of the test stand result that can be used for design purposes:

$$
\begin{align*}
& \left(J_{m}+g^{2} J_{s}+\left(g P_{h}\right)^{2} M_{l}\right) \dot{\omega}_{m}+\left(B+K_{t} K_{b} / R_{a}\right) \omega_{m}=\frac{2 \pi g P_{h} F_{l}}{\eta_{r}}+\frac{\eta_{g} K_{t} E_{i n}}{R_{a}}  \tag{III.3}\\
& \left(\frac{J_{m}}{\left(g P_{h}\right)^{2}}+\frac{J_{s}}{P_{h}^{2}}+M_{l}\right) \dot{V}_{l}+\frac{B}{\left(g P_{h}\right)^{2}} V_{l}=\frac{F_{l}}{\eta_{r}}+\frac{\eta_{g} K_{t} E_{i n}}{2 \pi g P_{h} R_{a}}
\end{align*}
$$

## III.2. Hydraulic Actuation Design

The two experiments that require accurate force/displacement trajectories will place significant demands on the hydraulic actuation system to be used. The first of these is an experiment meant to simulate the shock loading caused by the nozzle startup and shutdown transients. The TTB tests have led the authors to consider a force/time trajectory as shown in Figure III.2. This force/time trajectory is representative of several of the larger force pulses seen in the TTB 19 tests reported in Eric Earhart's memo to John Harbison dated on October of 1990. The peak magnitude of this force
also matches the peak force that appears to have been generated in the latest TTB tests that occurred in July, 1994 though calibrated data is not yet available. This force profile is assumed for the design of the hydraulic system but other profiles will be possible.


Figure III.2. Shock Loading Profile.

This shock loading profile must be executed by the hydraulics while motion is induced on the roller screw. Though the least restrictive design would be to assume a TTB test stiff arm is resisting this force to determine the displacements that must be accommodated, such a design might preclude experimentation with force accommodating control algorithms that generate larger motions. Since the displacements that might be so generated are unknown, a compromise design approach is to use a passive actuator response to determine the displacements expected. In determining the passive actuator response we use parameters that tend to minimize system inertia as viewed from the linear load. A direct drive system with a large lead is just such a system. To design for such an experiment, the motor torque is made zero and the above equation referred to the linear motion variable (III.1b) is numerically integrated to predict response. Though an analytical expression for the input is easily obtained, the nonlinear treatment of the system efficiency precludes a simple analytic solution for the response. Hence numerical integration is used to predict system response. The parameters assumed for this response are $\mathrm{P}_{\mathrm{h}}=.02 \mathrm{~m} / \mathrm{rev}, \mathrm{J}_{\mathrm{S}}=3.7$
$(10)^{-4} \mathrm{~kg}-\mathrm{m}^{2}, \mathrm{~g}=1$, and the electrical motor parameters can be ignored because the motor will be open circuited for a passive response analysis. The linear mass is 89 kg and $\eta_{\mathrm{n}}$ is 0.9 . Considering that the efficiency losses always act to remove energy from the system, this experiment is modeled in the linear motion parameter by multiplying or dividing the input force by the efficiency. The equation used for this simple simulation results directly by setting $\mathrm{T}_{\mathrm{m}}$ to zero in (III.1b). The direct and indirect efficiencies of roller screws can both fall in the $80 \%$ range although $90 \%$ is assumed here to generate larger estimates of actuator motion. In the case where energy is being stored in the system inertia, the applied force is diminished. In the other case where this energy is being removed by work against the applied force, the applied force is amplified. The numerical values resulting from the above-listed parameters are given in (III.4) below. Performing a numerical integration of this equation using the above depicted input force yields the response shown in Figures III. 3 and III. 4 below.

$$
\begin{equation*}
\left(\frac{0.00037}{0.0004}+89\right) \dot{V}_{l}=\frac{F_{l}}{0.9} \tag{III.4}
\end{equation*}
$$

The simulation results obtained is used to make choices about the performance requirements for the hydraulics. Specifically, stroke and flow rate requirements are obtained indicating that a minimum stroke is required (less than a couple of centimeters) and a flow rate of $0.03 *$ A meters cubed per second for the oil flow rates should satisfy the requirements of this experiment. As an additional, worst-case bound on the motion requirements for this experiment, if the system is considered $100 \%$ efficient, the maximum displacement is still under one millimeter in each direction and the maximum velocity is under $24 \mathrm{~mm} / \mathrm{s}$. Since it is required to produce the peak force in spite of the velocity which may have developed, ignoring phasing between these quantities, the area $A$ of the cylinder multiplied by the system pressure minus the pressure loss across the servo valve should produce the desired load:

$$
\begin{equation*}
\mathrm{A}(3000-\Delta \mathrm{P}(1 \mathrm{in} / \mathrm{s}))=100,000 \tag{III.5}
\end{equation*}
$$

Since servo valve being considered for this system will cause a pressure drop of at most 600 psi at these flow rates so the area A is determined to be 38.5 square inches with a resulting bore of 7 inches. The design analysis of this experiment does not lead directly to either pump sizing requirements or accumulator sizing requirements since the motions and oil use are so small. The accumulator will be charged and the pump shut down before this experiment is run.


Figure III.3. Displacement Due to Shock Loading with Minimum Actuator Inertia.


Figure III.4. Velocity Due to Shock Loading with Minimum Screw Inertia.

The design for the test intended to simulate a SSME TVC launch is more constrained because both the displacement and force trajectories are specified. Though the exact mission requirements change with each launch, it is generally thought that an actuator that can drive against a $30,000 \mathrm{lb}$. load at 6 inches per second while maintaining sufficient accuracy can perform the required mission. Though several typical mission scenarios can be found in the literature, it seems that a full stroke up and back of 12 inches at 6 inches per second is the most demanding requirement. A more typical requirement is motion at 1 inch per second. A rigorous test sequence made up of pairs of such motions is planned that will last over the roughly 300 second first stage of the launch followed by a sequence of 1 inch per second cycles over the following 300 seconds. One of the pairs of motions is depicted in Figure III. 5 below. The load is initially planned to be unidirectional for this application with a 30,000 load resisting extension of the actuator. Because all tests involving hydraulic actuation are relatively brief ( 10 minutes maximum), a constant pumping power solution will be used involving an inexpensive gear pump rather than a variable flow pressure compensated pump. Excess oil not needed to supply the accumulator or servo valve will be recirculated though a relief valve. The thermal energy generated at the relief valve will initially be stored in the oil reservoir. If this proves an insufficient heat sink, the relief valve will be cooled.

The accumulator and pump are sized to be able to perform pairs of fast and slow extend and retract cycles. During fast motions, the accumulator supplies the oil flow that is beyond the capability of the pump. During slow motions, the pump supplies the oil to the cylinder while also recharging the accumulator. This design reduces the cost of the overall system and eliminates the dynamics of a pressure compensated pump from consideration. A schematic of the hydraulic loading system is shown in Figure III. 6 below. Not shown in the schematic is the connection of the servo valve to the control computer, servo amplifier and load cell. Rather that use a pressure
measurement in the cylinder, we will use the force measurement provided by the axial load cell to control the hydraulic system.


Time (s)

Figure III.5. Full Stroke Cycle Pair for Mission Simulation.


Figure III.6. Schematic of hydraulic loading system.

A physical representation of the loading system is shown in Figure III.7. The components specified to build this system are listed in Table III.1. Custom cylinders are being built that simplify mounting to the test stand and reduce the cost of the system. These cylinders are also designed to support a significant transverse load as may be required by the misalignment coupling.

Table III.1. Hydraulic Equipment Specification.

| Item | Description |
| :---: | :--- |
| 1 | Bosch 0-510-825-006 17 GPM gear pump |
| 2 | Bosch PVQ-06-20B foot bracket w/B90 bolt kit for pump mounting |
| 3 | Bosch 0-531-115-610 5 gallon accumulator |
| 4 | 2 Accumulator Ball Valves |
| 5 | Bosch Accumulator Clamp 1-531-316-005 |
| 6 | Bosch Accumulator Bracket 1-531-334-000 |
| 7 | Bosch 0-811-404-206 NG 16 (D07) 34 gpm servo solenoid valve |
| 8 | Bosch 9-000-010-201 Valve Subplate |
| 9 | Bosch B-231 Subplate bolt kit |
| 10 | Bosch B-830-303-343 P/Q card servo valve control amp |
| 11 | Parker C 1600S check valve |
| 12 | Bosch FEI-PBEH-T06S relief valve set at 3200 psi |
| 13 | Wika 213.40-0-5000 LM pressure gage 0-5000 psi pressure range |
| 14 | Parker needle valve |
| 15 | FLO-EZY P30-1 1/2 - 100RV3 suction strainer (100 mesh) |
| 16 | Lenz T550-5 sight level gage |
| 17 | Lenz FCS-537reservoir filler cap |
| 18 | 50 gallon hydraulic reservoir |
| 19 | 2 reservoir end covers |
| 20 | Labor and Materials on Reservoir Unit Fabrication* |
| 21 | DTE fabricated cylinder with 13" stroke, 4" bore, 2.5" rod, see drawing |
| 22 | DTE fabricated cylinder with 4" stroke, 7" bore, 3" rod, see drawing |
| 23 | 6 micron return line filter |
| 24 | shaft coupling between motor and pump |



Figure III.7. Physical Layout of Hydraulic Loading System.

## III.3. Current Status of Mechanical Preparations

The completion of the test stand is behind schedule. We now plan to be conducting experiments in September. The status of major tasks as defined in the previous interim report is given below. Some tasks have changed as the system design was modified.

Table III.2. Test Stand Development Status.

| Task/Item | Status |
| :--- | :--- |
| frame: end beams | complete |
| frame: side beams | complete |
| main frame mounting | complete |
| end-of-screw machining | complete |
| main gear spacer | complete |
| bearing nut and backing plate | complete |
| linear bearing system | complete |
| main bearing housing | complete |
| nut cage | complete |
| flanged axial loading pipe | complete |
| nut carrier for linear bearings | complete, not mounted |
| misalignment coupling | flanges to be welded |
| transverse loading system | complete, not mounted |
| transverse slide | rework due 9/7 |
| main electric drive motor | arrived |
| transverse loading load cell | arrived \& mounted |
| torque \& axial load cell | arrived from A\&L |
| hydraulic loading system | in progress, due $9 / 7$ |
| motor drive and controls | in progress, due $9 / 7$ |
| gear reduction for motor | to be purchased |
| control and data acquisition | arrived, in development |

## APPENDIX A

## Digital Signal Processor Evaluation Board Data

## FEATURES

Superscalar IEEE Floating-Point Processor
Off-Chip Harvard Architecture Maximizes Signal Processing Performance
30 ns, 33.3 MIPS Instruction Rate, Single-Cycle Execution
100 MFLOPS Peak, 66 MFLOPS Sustained Performance
1024-Point Complex FFT Benchmark: 0.58 ms
Divide ( $\mathrm{y} / \mathrm{x}$ ): 180 ns
Inverse Square Root ( $1 / \backslash \overline{\mathrm{x}}$ ): 270 ns
32-Bit Single-Precision and 40-Bit Extended-Precision IEEE Floating-Point Data Formats
32-Bit Fixed-Point Formats, Integer and Fractional, with 80-Bit Accumulators
IEEE Exception Handling with Interrupt on Exception
Three Independent Computation Units: Multiplier, ALU, and Barrel Shifter
Dual Data Address Generators with Indirect, Immediate, Modulo, and Bit Reverse Addressing Modes
Two Off-Chip Memory Transfers in Parallel with Instruction Fetch and Single-Cycle Multiply \& ALU Operations
Multiply with Add \& Subtract for FFT Butterfly Computation
Efficient Program Sequencing with Zero-Overhead Looping: Single-Cycle Loop Setup
Single-Cycle Register File Context Switch
15 (or 25) ns External RAM Access Time for Zero-Wait-
State, 30 (or 40) ns Instruction Execution
IEEE JTAG Standard 1149.1 Test Access Port and On-Chip Emulation Circuitry
223-Pin PGA Package (Ceramic)

## GENERAL DESCRIPTION

The ADSP-21020 is the first member of Analog Devices' family of single-chip IEEE floating-point processors optimized for digital signal processing applications. Its architecture is similar to that of Analog Devices" ADSP-2100 family of tixed-point DSP processurs.
Fabricated in a high-speed, low-power CMOS process, the ADSP-21020 has a 30 ns instruction cycle time. With a highperformance on-chip instruction cache, the ADSP-21020 can execute every instruction in a single cycle.
The ADSP- 21020 features:

- Independent Parallel Computation Units

The arithmetic/logic unit ALU゙), multiplier and shifter per-
form ingle-cycle instructions. The units are architecturally arranged in parallel, maximizing computational throughput. A single multifunction instruction executes parallel ALC and multeplier operations. These computation units support IEEE

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FUNCTIONAL BLOCK DIAGRAM


32-bit single-precision floating-point, extended precision +0 -bit floating-point, and 32 -bit fixed-point data formats.

- Data Register File

A general-purpose data register file is used for transferring data between the computation units and the data buses, and for storing intermediate results. This 10 -port ( 16 -register) register file, combined with the ADSP-21020's Harvard architecture, allows unconstrained data flow between computation units and off-chip memory.

- Single-Cycle Fetch of Instruction and Two Operands The ADSP-21020 uses a modified Harvard archirecture in which data memory stores dara and program memory stores both instructions and data. Because of its separate program and data memory buses and on-chip instruction cache, the processor can simultaneously fetch an operand from data memory, an operand from program memory, and an instruction from the cache, all in a single cycle.
- Memory Interface

Addressing of external memory devices by the ADSP-21020 is facilitated by on-chip decoding of high-order address lines to generate memory bank select signals. Separate control lines are also generated for simplified addressing of page-mode DRAM.
The ADSP-21020 provides programmable memory wait states, and external memory acknowledge controls allow interfacing to peripheral devices with variable access times.

- Instruction Cache

The ADSP-21020 includes a high performance instruction cache that enables three-bus operation for fetching an instruction and two data values. The cache is selective - only the

## ADSP-21020

instructions whose fetches conflict with program memory data accesses are cached. This allows full-speed execution of core, looped operations such as digital filter multiply-accumulates and FFT butterfly processing.

## - Hardware Circular Buffers

The ADSP-21020 provides hardware to implement circular buffers in memory, which are common in digital filters and Fourier transform implementations. It handles address pointer wraparound, reducing overhead thereby increasing performance) and simplifying implementation. Circular buffers can start and end at any location.

- Flexible Instruction Set

The ADSP-21020's 48 -bit instruction word accommodates a variety of parallel operations, for concise programming. For example, the ADSP-21020 can conditionally execute a multiply, an add, a subtract and a branch in a single instruction.

## DEVELOPMENT SYSTEM

The ADSP-21020 is supported with a complete set of software and hardware development tools. The ADSP-21000 Family Development System includes development software, an evaluation board and an in-circuit emulator.

## - Assembler

Creates relocatable, COFF :Common Object File Format) object files from ADSP-21xxx assembly source code. It accepts standard $C$ preprocessor directives for conditional assembly and macro processing. The algebraic syntax of the ADSP-2 1 xxx assembly language facilitates coding and debugging of DSP algorithms.

- Linker/Librarian

The Linker processes separately assembled object files and library files to create a single executable program. It assigns memory locations to code and to data in accordance with a user-defined architecture file that describes the memory and I/O configuration of the target system. The Librarian allows you to group frequently used object files into a single library file that can be linked with your main program.

- Simulator

The Simulator performs interactive, instruction-level simulation of ADSP-21 xxx code within the hardware configuration described by a system architecture file. It flags illegal operations and supports full symbolic disassembly. It provides an easy-to-use, window oriented, graphical user interface that is identical to the one used by the ADSP-21020 EZ-ICE Emulator. Commands are accessed from pull-down menus with a mouse.

- PROM Splitter

Formats an executable file into files that can be used with an industry-standard PROM programmer.

- C Compiler and Runtime Library

The C Compiler complies with ANSI specifications and has been validated to the widely used Plum-Hall Validation Suite as well as the Perennial Validation Suite. It takes advantage of the ADSP-21020's high-level language architectural features and incorporates optimizing algorithms to speed up the execution of code. It includes an extensive runtime library with over 100 standard and DSP-specific functions.

- C Source Level Debugger

A full-featured $C$ source level debugger that works with the simulator or EZ-ICE emulator to allow dehugging of assembler source, $C$ source or mixed assembler and $C$.

- DSP/C… Compiler Available First Half 1993

Supports A.NSI Standard (X3J11.1) Sumerical C as defined br the Numeric C Extensions Group. The DSP/C'" Compiler accepts $C$ source input containing Numerical $C$ extensions for array selection, vector math operations. complex data types, circular pointers, and variably dimensioned arrays, and outputs ADSP-21xxx assembly language source code.

- ADSP-21020 EZ-LAB Evaluation Board

The EZ-LAB Evaluation Board is a general-purpose, standalone ADSP-21020 system that includes 32 K words of program memory and 32 K words of data memory as well as analog I/O. A PC RS- 232 download path enables the user to downioad and run programs directly on the EZ-L.AB. In addition, it may be used in conjunction with the EZ-ICE Emulatur to provide a powerful software debug environment.

- ADSP-21020 EZ-ICE Emulator

This in-circuit emulator provides the system designer with a PC-based development environment that allows nonintrusive access to the ADSP-21020's internal registers through the processor’s 5-pin JTAG Test Access Port. This use of on-chip emulation circuitry enables reliable, full-speed performance in any target. The emulator uses the same graphical user interface as the ADSP-21020 Simulator, allowing an easy transition from software to hardware debug. (See "Target System
Requirements for L'se of EZ-ICE Emulator" on page 27.)

## ADDITIONAL INFORMATION

This data sheet provides a general overview of ADSP-21020 functionality. For additional information on the architecture and instruction set of the processor, refer to the $-A D S P-21020$ User's Lianual. For development system and programming reference information, refer to the $A D S P-21000$ Family Development Software Manuals and the ADSP-21020 Programmer's Quick Reference. Applications code listings and benchmarks tor key DSP algorithms are available on the DSP Applications BBS; call (617) $461-4258,8$ data bits, no parity, 1 stop bit, 300/1200/2400/9600 baud.

## ARCHITECTURE OVERVIEW

Figure 1 shows a block diagram of the ADSP-21020. The processor fearures:

- Three Computation Cinits ALC, Multiplier, and Shifter with a Shared Dara Register File
- Two Data Address Generators (DAG 1. DAG 2
- Program Sequencer with Instruction Cache
- 32-Bit Timer
- Memory Buses and Interface
- JTAG Test Access Port and On-Chip Emulation Support


## Computation Units

The ADSP-21020 contains three independent computation units: an ALC, a multiplier with fixed-point accumulator, and a shifter. In order to meet a wide variety of processing needs, the computation units process data in three formats: 32 -bit fixed-point, 32-bit floating-point and 40 -bit floating-point. The tluating-point operations are single-precision IEEE-compatible IEEE Standard $75+854$. The 32-hit thating-foint format is the standard IEEE format. whereas the +()-hit IEEE single-extended-precision format has cight additional L S B of mantissa tor greater accuracy.




Figure 1. ADSP-21020 Block Diagram

The multiplier performs floating-point and fixed-point multiplication as well as fixed-point multiply/add and multiply/subtract operations. Integer products are 64 bits wide, and the accumulator is 80 bits wide. The ALU performs 45 standard arithmetic and logic operations, supporting both fixed-point and floatingpoint formats. The shifter performs 19 different operations on 32 -bit operands. These operations include logical and arithmetic shifts, bit manipulation, field deposit, and extract and derive exponent operations.
The computation units perform single-cycle operations; there is no computation pipeline. The three units are connected in parallel rather than serially, via multiple-bus connections with the 10 -port data register file. The ourput of any computation unit may be used as the input of any unit on the next cycle. In a multifunction computation, the ALU and multiplier perform independent, simultaneous operations.

## Data Register File

The ADSP-21020's general-purpose data register file is used for transferring data between the computation units and the data buses, and for storing intermediate results. The register file has two sets (primary and alternate of sixteen +0 -bit registers each, for fast context switching.
With a large number of buses connecting the registers to the computation units, data flow between computation units and from/to off-chip memory is unconstrained and free from bottlenecks. The 10 -port register file and Harvard architecture of the

ADSP-21020 allow the following nine data transfers to be performed every cycle:

- Off-chip read/write of two operands to or from the register file
- Two operands supplied to the ALU
- Two operands supplied to the multiplier
- Two results received from the ALU and multiplier (three, if the ALU operation is a combined addition/subtraction)
The processor's 48 -bit orthogonal instruction word supports fully parallel data transfer and arithmetic operations in the same instruction.


## Address Generators and Program Sequencer

Two dedicated address generators and a program sequencer supply addresses for memory accesses. Because of this, the computation units need never be used to calculate addresses. Because of its instruction cache, the ADSP-21020 can simultaneously fetch an instruction and data values from both off-chip program memory and off-chip data memory in a single cycle.
The data address generators (DAGs) provide memory addresses when external memory data is transferred over the parallel memory ports to or from internal registers. Dual data address generators enable the processor to output two simultaneous addresses for dual operand reads and writes. DAG 1 supplies 32 -bit addresses to data memory. DAG 2 supplies 24 -bit addresses to program memory for program memory data accesses.

Each DAG keeps track of up to eight address pointers, eight modifiers, eight buffer length values and eight base values. A pointer used for indirect addressing can be modified by a value in a specified register, either before (premodify) or after (postmodify) the access. To implement automatic modulo addressing for circular buffers, the ADSP-21020 provides buffer length registers that can be associated with each pointer. Base values for pointers allow circular buffers to be placed at arbitrary locations. Each DAG register has an alternate register that can be activated for fast context switching.
The program sequencer supplies instruction addresses to program memory. It controls loop iterations and evaluates conditional instructions. To execute looped code with zero overhead, the ADSP-21020 maintains an internal loop counter and loop stack. No explicit jump or decrement instructions are required to maintain the loop.
The ADSP-21020 derives its high clock rate from pipelined fetch, decode and execute cycles. Approximately $70 \%$ of the machine cycle is available for memory accesses; consequently, ADSP-21020 systems can be built using slower and therefore less expensive memory chips.

## Instruction Cache

The program sequencer includes a high performance, selective instruction cache that enables three-bus operation for fetching an instruction and two data values. This two-way, set-associative cache holds 32 instructions. The cache is selective-only the instructions whose fetches conflict with program memory data accesses are cached, so the ADSP-21020 can perform a program memory data access and can execute the corresponding instruction in the same cycle. The program sequencer fetches the instruction from the cache instead of from program memory, enabling the ADSP-21020 to simultaneously access data in both program memory and data memory.

## Context Switching

Many of the ADSP-21020's registers have alternate register sets that can be activated during interrupt servicing to facilitate a fast context switch. The data registers in the register file, DAG registers and the multiplier result register all have alternate sets. Registers active at reset are called primary registers; the others are called alternate registers. Bits in the MODE1 control register determine which registers are active at any particular time.
The primary/alternate select bits for each half of the register file (top eight or bottom eight registers) are independent. Likewise. the top four and bottom four register sets in each DAG have independent primary/alternate select bits. This scheme allows passing of dara berween contexts.

## Interrupts

The ADSP-21020 has four external hardware interrupts, nine internally generated interrupts, and eight software interrupts. For the external interrupts and the internal timer interrupt, the ADSP-21020 automatically stacks the arithmetic status and mode (MODE1' registers when servicing the interrupt, allowing five nesting levels of fast service for these interrupts.
An interrupt can occur at any time while the ADSP-21020 is executing a program. Internal events that generate interrupts include arithmetic exceptions, which allow for fast trap handling and recovery.

## Timer

The programmable interval timer provides periodic interrupt generation. When enabled, the timer decrements a 3-bit count
register every cycle. When this count register reaches zero, the ADSP-21020 generates an interrupt and asserts its TIMEXP output. The count register is automatically reloaded from a 32 -bit period register and the count resumes immediately.

## System Interface

Figure 2 shows an ADSP- 21020 basic system configuration.
The external memory interface supports memory-mapped peripherals and slower memory with a user-defined combination of programmable wait states and hardware acknowledge signals. Bota the program memory and data memory interfaces support addressing of page-mode DRA.IIs.
The ADSP-21020's internal functions are supported by four internal buses: the program memory address (PMA) and data memory address (DMA; buses are used for addresses associated with program and data memory. The program memory data (PMD) and data memory data (DMD) buses are used for data associated with the two memory spaces. These buses are extended off chip. Four data memory select (DMS) signals select one of four user-configurable banks of data memory. Similarly, two program memory select (PMS) signals select between two user-configurable banks of program memory. All banks are independently programmable for $0-7$ wait states.
The PX registers permit passing data between program memory and data memory spaces. They provide a bridge between the 48 -bit PMD bus and the 40 -bit DMD bus or between the 40 -bit register file and the PMD bus.

The PMA bus is $2+$ bits wide allowing direct access of up to 16 M words of mixed instruction code and data. The PMD is 48 bits wide to accommodate the 48 -bit instruction width. For access of 40 -bit dara the lower 8 bits are unused. For access of 32 -bit data the lower 16 bits are ignored.
The DMA bus is 32 bits wide allowing direct access of up to 4 Gigawords of data. The DMD bus is 40 bits wide. For 32 -bit data, the lower 8 bits are unused. The DMD bus provides a path for the contents of any register in the processor to be transferred to any other register or to any external data memory location in a single cycle. The data memory address comes from one of two sources: an absolute value specified in the instruction code (direct addressing; or the output of a data address generator (indirect addressing),
External devices can gain control of the processor's memory buses from the ADSP-21020 by means of the bus request/grant signals $(\overline{\mathrm{BR}}$ and $\overline{\mathrm{BG}})$. To grant its buses in response to a bus request, the ADSP-21020 halts internal operations and places its program and data memory interfaces in a high impedance state. In addition, three-state controls ( $\overline{\text { DMTS }}$ and $\overline{\text { PMTS }) ~ a l l o w ~ a n ~ e x t e r n a l ~}$ device to place either the program or data memory interface in a high impedance state without affecting the other interface and without halting the ADSP-21020 unless it requires a memory access from the affected interface. The three-state controls make it easy for an external cache controller to hold the ADSP-21020 off the bus while it updates an external cache memory.

## JTAG Test and Emulation Support

The ADSP- 21020 implements the boundary scan testing provisions specified by IEEE Standard 11+9.1 of the Joint Testing Action Group JTAG. The ADSP-21020's test access port and on-chip JTAG circuitry is fully compliant with the IEEE 1149.1 specification. The test decess port enables boundary scan testing of circtiter connected to the ADSP-21020's $\mathrm{I} /()$ pins.


Figure 2. Basic System Configuration

The ADSP-21020 also implements on-chip emulation through the JTAG test access port. The processor's eight sets of breakpoint range registers enable program execution at full speed until reaching a desired breakpoint address range. The processor can then halt and allow reading/writing of all the processor's internal registers and external memories through the JTAG port.

## PIN DESCRIPTIONS

This section describes the pins of the ADSP-21020. When groups of pins are identified with subscripts, e.g. PMD ${ }_{+7-0}$, the highest numbered pin is the MSB (in this case, $\mathrm{PMD}_{+7}$ ). Inputs identified as synchronous ( $S$ ) must meet timing requirements with respect to CLKIN (or with respect to TCK for TMS, TDI, and TRST). Those that are asynchronous (A) can be asserted asynchronously to CLKIN.

$$
\begin{aligned}
& O=\text { Output; } I=\text { Input: } S=\text { Synchronous: } A=\text { Asynchronous: } \\
& P=\text { Power Supply: } G=\text { Ground. }
\end{aligned}
$$

| Pin <br> Name | Type | Function |
| :---: | :---: | :---: |
| PMA $_{23-0}$ | O | Program Memory Address. The ADSP-21020 outputs an address in program memory on these pins. |
| $\mathrm{PMD}_{47-0}$ | I/O | Program Memory Data. The ADSP- 21020 inputs and outputs data and instructions on these pins. 32 -bit fixed-point data and 32 -bit single-precision floating-point data is transferred over bits 47-16 of the P.MD bus. |
| $\overline{\mathrm{PMS}}_{1-11}$ | 0 | Program Memory Select lines. These pins are asserted as chip selects for the corresponding banks of program memory. Memory banks must be defined in the memory control registers. These pins are decoded program memory address lines and provide an early indication of a possible bus cycle. |
| $\overline{\text { PMRD }}$ | 0 | Program Memory Read strobe. This pin is asserted when the ADSP-21020 reads from program memory. |
| $\overline{\text { PMWR }}$ | 0 | Program Memory Write strobe. This pin is asserted when the ADSP-21020 writes to program memory |
| PMACK | 1 S | Program Memory Acknowledge. An external device deasserts this input to add wait states (0) a memory aciess. |


| Pin <br> Name | Type | Function |
| :--- | :--- | :--- | | PMPAGE O | Program Memory Page Boundary. The <br> ADSP-21020 asserts this pin to signal that a <br> program memory page boundary has been <br> crossed. Memory pages must be defined in <br> the memory control registers. |
| :--- | :--- |
| Program Memory Three-State Control. $\overline{\text { PMTS }}$ |  |


| Pin <br> Name | Type | Function |
| :---: | :---: | :---: |
| DMPAGE | O | Data Memory Page Boundary. The ADSP21020 asserts this pin to signal that a data memory page boundary has been crossed. Memory pages must be defined in the memory control registers. |
| $\overline{\text { DMTS }}$ | I/S | Data Memory Three-State Control. $\overline{\text { DMTS }}$ places the data memory address, data, selects, and strobes in a high-impedance state. If a DM access occurs while DMTS is asserted, the processor will halt and the memory access will not be completed. DMACK must be asserted for at least one cycle when DMTS is deasserted to allow any pending memory access to complete properly. See the Memory Interface chapter of the User's Manual for details on using DMTS. |
| CLKIN | I | External clock input to the ADSP-21020. The instruction cycle rate is equal to CLKIN. CLKIN may not be halted, changed, or operated below the specified frequency. |
| $\overline{\text { RESET }}$ | I/A | Sets the ADSP-21020 to a known state and begins execution at the program memory location specified by the hardware reser vector (address). This input must be asserted (low) at power-up. |
| $\overline{\mathrm{IRQ}}_{3-0}$ | I/A | Interrupt request lines; may be either edgetriggered or level-sensitive. |
| $\mathrm{FLAG}_{3-0}$ | I/O/A | External Flags. Each is configured via control bits as either an input or output. As an input, it can be tested as a condition. As an output, it can be used to signal external peripherals. |
| $\overline{\mathrm{BR}}$ | I/A | Bus Request. Used by an external device to request control of the memory interface. When $\overline{\mathrm{BR}}$ is asserted, the processor halts execution after completion of the current cycle, places all memory data, addresses, selects, and strobes in a high-impedance state, and asserts $\overline{\mathrm{BG}}$. The processor continues normal operation when $\overline{\mathrm{BR}}$ is released. |
| $\overline{\mathrm{BG}}$ | O | Bus Grant. Acknowledges a bus request ( $\overline{\mathrm{BR}}$ ), indicating that the external device may take control of the memory interface. $\overline{\mathrm{BG}}$ is asserted (held low) until $\overline{\mathrm{BR}}$ is released. |
| TIMEXP | 0 | Timer Expired. Asserted for four cycles when the value of TCOUNT is decremented to zero. |
| RCOMP |  | Compensation Resistor input. Controls compensated output buffers. Connect RCOMP through a $1.8 \mathrm{k} \Omega=15 \%$ resistor to EVDD. Use of a capacitor (approximately 100 pF ), placed in parallel with the 1.8 kS resistor is recommended. |
| EVDD | P | Power supply (for output drivers), nominally +5 V de 10 pins:. |
| EGND | G | Power supply return for output drivers); (16 pins : |
| IVDD | P | Power supply for internal circuitry , nominally -5 V de + pins: |

 of poop gualter

| Pin <br> Name | Type | Function |
| :--- | :--- | :--- |
| IGND | G | Power supply return (for internal circuitry); <br> (7 pins ). |
| TCK | I | Test Clock. Provides an asynchronous clock <br> for JTAG boundary scan. |
| TMS | I/S | Test Mode Select. Used to control the test <br> state machine. TMS has a 20 k $\Omega$ internal <br> pullup resistor. |
| TDI | I/S | Test Data Input. Provides serial data for the <br> boundary scan logic. TDI has a 20 k $\Omega$ inter- <br> nal pullup resistor. |
| TDO | O | Test Data Output. Serial scan output of the <br> boundary scan path. |
| TRST | I/A | Test Reser. Resets the test state machine. <br> TRST must be asserted (pulsed low) after <br> power-up or held low for proper operation of <br> the ADSP-21020. TRST has a 20 k $\Omega$ internal <br> pullup resistor. <br> No Connect. No Connects are reserved pins <br> that must be left open and unconnected. |

## INSTRUCTION SET SUMMARY

The ADSP-21020 instruction set provides a wide variety of programming capabilities. Every instruction assembles into a single word and can execute in a single processor cycle. Multifunction instructions enable simultaneous multiplier and ALU operations, as well as computations executed in parallel with data transfers. The addressing power of the ADSP-21020 gives you flexibility in moving data both internally and externally. The ADSP-21020 assembly language uses an algebraic syntax for ease of coding and readability.
The instruction types are grouped into four categories:

```
Compute and Move or Modify
Program Flow Control
Immediate Move
Miscellaneous
```

The instruction types are numbered; there are 22 types. Some instructions have more than one syntactical form; for example, Instruction + has four distinct forms. The instruction number itself has no bearing on programming, but corresponds to the opcode recognized by the ADSP-21020 device.
Because of the width and orthogonality of the instruction word, there are many possible instructions. For example, the ALU supports 21 fixed-point operations and 24 floating-point operations; each of these operations can be the compute portion of an instruction.
The following pages provide an overview and summary of the ADSP-21020 instruction set. For complete information, see the ADSP-21020 User's Manual. For additional reference information, see the ADSP-21020 Programmer's Quick Reference.

This section also contains several reference tables for using the instruction set.

- Table I describes the notation and abbreviations used.
- Table II lists all condition and termination code mnemonics.
- Table III lists all register mnemonics.
- Tables IV through VII list the syntax for all compute (ALU, multiplier, shifter or multifunction : operations.
- Table VIII lists interrupts and their vector addresses.


## COMPUTE AND MOVE OR MODIFY INSTRUCTIONS

| 1. |  | compute, | $\left\|\begin{array}{l} D M(\mathrm{Ia}, \mathrm{Mb})=\text { dreg } 1 \\ \mathrm{dreg} 1=\mathrm{DM}(\mathrm{I}, \mathrm{Mb}) \end{array}\right\|$ | $\left.\begin{aligned} & \mathrm{PM}(\mathrm{Ic}, M \mathrm{M})=\mathrm{dreg} 2 \\ & \mathrm{dreg} 2=\mathrm{PM}(\mathrm{Ic}, \mathrm{Md}) \end{aligned} \right\rvert\,$ |
| :---: | :---: | :---: | :---: | :---: |
| 2. | IF condition | compute ; |  |  |
| 3 a. | IF condition | compute, | $\left\|\begin{array}{l}\mathrm{DM}(\mathrm{Ia}, \mathrm{Mb}) \\ \mathrm{PM}(\mathrm{Ic}, \mathrm{Md})\end{array}\right\|=$ ureg ; |  |
| 3 b . | IF condition | compute, | $\left\|\begin{array}{l}\mathrm{DM}(\mathrm{Mb}, \mathrm{Ia}) \\ \mathrm{PM}(\mathrm{Md}, \mathrm{Ic})\end{array}\right\|=$ ureg ; |  |
| 3 c. | IF condition | compute, | ureg $=\left\|\begin{array}{l}\mathrm{DM}(\mathrm{Ia}, \mathrm{Mb}) \\ \mathrm{PM}(\mathrm{Ic}, \mathrm{Md})\end{array}\right\|$; |  |
| 3 d. | $I F$ condition | compute, | ureg $=\left\|\begin{array}{l}\text { DM(Mb, Ia }) \\ \operatorname{PM}(\mathrm{Md}, \mathrm{Ic})\end{array}\right\|$; |  |
| 4 a. | IF condition | compute, | $\left\|\begin{array}{l}\text { DM }(\text { Ia, }<\text { data } 6>) \\ \operatorname{PM}(\text { Ic, <data6>) }\end{array}\right\|=$ dreg ; |  |
| 4 b. | $I F$ condition | compute, | $\left\|\begin{array}{l}\text { DM }(<\text { data } \gg, \text { Ia }) \\ \mathrm{PM}(<\text { data6 }>, \mathrm{Ic})\end{array}\right\|=$ dreg ; |  |
| 4 c. | IF condition | compute, | dreg $=\left\|\begin{array}{l}\text { DM }(\text { Ia, <data } \ggg \\ \mathrm{PM}(\mathrm{Ic},<\mathrm{data} \times>)\end{array}\right\| ;$ |  |
| 4d. | IF condition | compute, | dreg $=\left\|\begin{array}{l}\text { DM }(<\text { data } \gg, \text { Ia }) \\ \mathrm{PM}(<\text { data }>, \mathrm{Ic})\end{array}\right\|$; |  |
| 5. | IF condition | compute, | uregl $=$ ureg 2 ; |  |
| 6 a. | IF condition | shiftimm, | $\left\|\begin{array}{l}D M(I a, M b) \\ P M(I c, M d)\end{array}\right\|=$ dreg ; |  |
| 6 b . | IF condition | shiftimm, | dreg $=\left\|\begin{array}{l}D M(I a, M b) \\ P M(I c, M d)\end{array}\right\| ;$ |  |
| 7. | IF condition | compute, | MODIFY $\left\|\begin{array}{l}(\mathrm{I} a, \mathrm{Mb}) \\ (\mathrm{Ic}, \mathrm{Md})\end{array}\right\|$; |  |

PROGRAM FLOW CONTROL INSTRUCTIONS

(DB) Delayed branch
(LA) Loop abort pop loop PC stacks on branch)

Table III. Universal Registers
Name

| Register File |  |
| :--- | :--- |
| R15-R0 | Register file locations |
| Program Sequencer |  |
| PC^ | Program counter; address of instruction |
|  | currently executing |
| PCSTK | Top of PC stack |
| PCSTKP | PC stack pointer |
| FADDR | Fetch address |
| DADDR^ | Decode address |
| LADDR | Loop termination address, code; top of loop |
|  | address stack |
| CURLCNTR | Current loop counter; top of loop count stack |
| LCNTR | Loop count for next nested counter-controlled loop |
| Data Address | Generators |
| I7-I0 | DAG1 index registers |
| M7-M0 | DAG1 modify registers |
| L7-L0 | DAG1 length registers |
| B7-B0 | DAG1 base registers |
| I15-I8 | DAG2 index registers |
| M15-M8 | DAG2 modify registers |
| L15-L8 | DAG2 length registers |
| B15-B8 | DAG2 base registers |
| Bus Exchange |  |
| PX1 |  |
| PMD-DMD bus exchange 1 (16 bits) | PMD |
| PX | PMD-DMD bus exchange 2 (32 bits) |
| P8-bit PX1 and PX2 combination |  |

$\begin{array}{ll}\text { Timer } & \\ \text { TPERIOD } & \text { Timer period } \\ \text { TCOUNT } & \text { Timer counter }\end{array}$
TCOUNT Timer counter
Memory Interface
DMWAIT Wait state and page size control for data memory
DMBANK1 Data memory bank 1 upper boundary
DMBANK2 Data memory bank 2 upper boundary
DMBANK3 Data memory bank 3 upper boundary
DMADR* Copy of last data memory address
PMWAIT Wait state and page size control for program memory
PMBANK1 Program memory bank 1 upper boundary
PMADR* Copy of last program memory address
System Registers
MODEI Mode control bits for bit-reverse, alternate registers, interrupt nesting and enable, ALU saturation, floating-point rounding mode and boundary
MODE2 Mode control bits for interrupt sensitivity, cache disable and freeze, timer enable, and I/O flag configuration
IRPTL Interrupt latch
IMASK Interrupt mask
IMASKP Interrupt mask pointer (for nesting)
ASTAT Arithmetic status flags, bit test, I/O flag values, and compare accumulator
STKY Sticky arithmetic status flags, circular buffer overflow flags, stack status flags (not sticky)
USTAT1 User status register 1
USTAT2 User status register 2
*read-only
Reter to User's Mantal tor bit-leed detinitions of each register.

## Table IV. ALU Compute Operations

| Fixed-Point | Floating-Point |
| :---: | :---: |
| $\mathrm{Rn}=\mathrm{Rx}+\mathrm{Ry}$ | $\mathrm{Fn}=\mathrm{Fx}+\mathrm{Fy}$ |
| $\mathrm{Rn}=\mathrm{Rx}-\mathrm{Ry}$ | $F \mathrm{n}=\mathrm{Fx}-\mathrm{Fy}$ |
| $\mathrm{Rn}=\mathrm{Rx}+\mathrm{Ry}, \mathrm{Rm}=\mathrm{Rx}-\mathrm{Ry}$ | $\mathrm{Fn}=\mathrm{Fx}+\mathrm{Fy}, \mathrm{Fm}=\mathrm{Fx}-\mathrm{Fy}$ |
| $\mathrm{Rn}=\mathrm{Rx}+\mathrm{Ry}+\mathrm{Cl}$ | $\mathrm{Fn}=\mathrm{ABS}(\mathrm{Fx}+\mathrm{Fy})$ |
| $\mathrm{Rn}=\mathrm{Rx}-\mathrm{Ry}+\mathrm{CI}-1$ | $\mathrm{Fn}=\mathrm{ABS}(\mathrm{Fx}-\mathrm{Fy})$ |
| $\mathrm{Rn}=(\mathrm{Rx}+\mathrm{Ry}) / 2$ | $\mathrm{Fn}=(\mathrm{Fx}+\mathrm{Fy}) / 2$ |
| $\operatorname{COMP}(\mathrm{Rx}, \mathrm{Ry})$ | $\operatorname{COMP}(\mathrm{Fx}, \mathrm{Fy})$ |
| $\mathrm{Rn}=-\mathrm{Rx}$ | $\mathrm{Fn}=-\mathrm{Fx}$ |
| $\mathrm{Rn}=\mathrm{ABS} \mathrm{Rx}$ | $\mathrm{F}_{\mathrm{n}}=\mathrm{ABS} \mathrm{Fx}$ |
| $\mathrm{Rn}=$ PASS $\mathrm{R} x$ | $\mathrm{Fn}_{\mathrm{n}}=\mathrm{PASS} \mathrm{FX}$ |
| $\mathrm{Rn}=\mathrm{MIN}(\mathrm{Rx}, \mathrm{Ry})$ | $\mathrm{Fr}=\mathrm{MIN}(\mathrm{Fx}, \mathrm{Fy})$ |
| $\mathrm{Rn}=\mathrm{MAX}(\mathrm{Rx}, \mathrm{Ry})$ | $\mathrm{Fn}=\mathrm{MAX}(\mathrm{Fx}, \mathrm{Fy})$ |
| $\mathrm{Rn}=\mathrm{CLIP} \mathrm{Rx}$ BY Ry | $\mathrm{Fn}=$ CLIP Fx BY Fy |
| $\mathrm{Rn}=\mathrm{Rx}+\mathrm{Cl}$ | $\mathrm{F}_{\mathrm{n}}=$ RND $\mathrm{Fx}_{\mathrm{x}}$ |
| $\mathrm{Rn}=\mathrm{Rx}+\mathrm{CI}-1$ | $\mathrm{Fn}=$ SCALB Fx BY Ry |
| $\mathrm{Rn}=\mathrm{Rx}+1$ | $\mathrm{Rn}=$ MANT Fx |
| $\mathrm{Rn}=\mathrm{Rx}-1$ | $\mathrm{Rn}=$ LOGB Fx |
| $\mathrm{Rn}=\mathrm{Rx}$ AND Ry | $\mathrm{Rn}=\mathrm{FIX}$ Fx BY Ry |
| $\mathrm{Rn}=\mathrm{Rx}$ OR Ry | $\mathrm{Rn}=\mathrm{FIX} \mathrm{Fx}$ |
| $\mathrm{Rn}=\mathrm{Rx}$ XOR Ry | $\mathrm{Fn}=\mathrm{FLOAT} \mathrm{Rx}$ BY Ry |
| $\mathrm{Rn}=\mathrm{NOT} R \mathrm{x}$ | $\mathrm{Fn}=\mathrm{FLOAT} \mathrm{Rx}$ |
|  | $\mathrm{Fn}=$ RECIPS Fx |
|  | $\mathrm{Fn}=$ RSQRTS Fx |
|  | $\mathrm{Fn}=\mathrm{Fx}$ COPYSIGN Fy |

$\mathrm{Rn}, \mathrm{Rx}, \mathrm{Ry}$ R15-R0; register file location, fixed-point
$F_{n}, F x, F y$ F1S-F0; register file location, floating point

Table V. Multiplier Compute Operations
$\left|\begin{array}{l}\mathrm{Rn} \\ \mathrm{MRF} \\ M R B\end{array}\right|$
$=\mathrm{Rx}{ }^{*} \mathrm{Ry}\left(\left|\begin{array}{l}S \\ U\end{array}\right|\left|\begin{array}{l}S \\ U\end{array}\right|\left|\begin{array}{l}F \\ I \\ F R\end{array}\right|\right)$
$\mathrm{Fn}=\mathrm{Fx}^{*} \mathrm{Fy}$

$\mathrm{Rn}, \mathrm{Rx}$, Ry R.15-R0; register file location, fixed-point
$\mathrm{Fn}, \mathrm{Fx}, \mathrm{Fy}$ F15-F0; register file location, floating-point
MRxF MR2F, MR1F; MR0F; multiplier result accumulators, foreground
MRxB MR2B, MR1B, MR0B; multiplier result accumulators, background
( $\mid x$-input $|\quad| y$-input $\left.|\quad| \begin{aligned} & \text { data format, } \\ & \text { rounding }\end{aligned} \right\rvert\,$ )
S Signed input
U Unsigned input
I Integer input(s)
F Fractional input(s)
FR Fractional inputs, Rounded output
(SF) Default format for 1 -input operations
(SSF) Default format for 2 -input operations

## Table VI. Shifter and Shifter Immediate Compute Operations

| Shifter | Shifter Immediate |
| :---: | :---: |
| Rn = LSHIFT Rx BY Ry | $\mathrm{Rn}=$ LSHIFT Rx BY<data $8>$ |
| $\mathrm{Rn}_{\mathrm{n}}=\mathrm{Rn}$ OR LSHIFT Rx BY Ry | $\mathrm{Rn}=\mathrm{Rn}$ OR LSHIFT $\mathrm{Rx} \mathrm{BY}<$ data $8>$ |
| $\mathrm{Rn}=$ ASHIFT Rx BY Ry | $\mathrm{Rn}=\mathrm{ASHIFT} \mathrm{Rx} \mathrm{BY}<$ data $8>$ |
| $\mathrm{Rn}=\mathrm{Rn}$ OR ASHIFT Rx BY Ry | $\mathrm{Rn}=\mathrm{Rn}$ OR ASHIFT $\mathrm{Rx} \mathrm{BY}<$ data $8>$ |
| $\mathrm{Rn}=\mathrm{ROT}$ Rx BYRY | $\mathrm{Rn}=\mathrm{ROT} \mathrm{Rx} \mathrm{BY}<$ data8 $>$ |
| $\mathrm{Rn}=\mathrm{BCLR}$ Rx BY Ry | Rn = BCLR Rx BY $<$ data8 $>$ |
| $\mathrm{Rn}=\mathrm{BSET} R \mathrm{Rx}$ BY Ry | $\mathrm{Rn}=$ BSET Rx BY $<$ data8 $>$ |
| Rn = BTGL Rx BY Ry | $\mathrm{Rn}=\mathrm{BTGL} \mathrm{Rx}$ BY $<$ data $8>$ |
| BTST Rx BY Ry | BTST Rx BY<data8> |
| $\mathrm{Rn}_{\mathrm{n}}=\mathrm{FDEP} \mathrm{Rx}$ BY Ry | $\mathrm{Rn}=\mathrm{FDEP} \mathrm{Rx}$ BY < bit6>: <len6> |
| $\mathrm{Rn}=\mathrm{Rn}$ OR FDEP Rx BY Ry | $\mathrm{Rn}=\mathrm{Rn}$ OR FDEP Rx $\mathrm{BY}<$ bit6>: <len6> |
| $\mathrm{Rn}=\mathrm{FDEP}$ Rx BY Ry (SE) | $\mathrm{Rn}=\mathrm{FDEP}$ Rx BY < bit6>: <len6> (SE) |
| $\mathrm{Rn}=\mathrm{Rn}$ OR FDEP Rx BY Ry (SE) | $\mathrm{Rn}=\mathrm{Rn}$ OR FDEP Rx $\mathrm{BY}<$ bit $6>$ : <len6> (SE) |
| Rn = FEXT Rx BY Ry | $\mathrm{Rn}=$ FEXT Rx BY < bit6>: <len6> |
| $\mathrm{Rn}=\mathrm{FEXT}$ Rx BY Ry (SE) | $\mathrm{Rn}=$ FEXT Rx $\mathrm{BY}<$ bit6>: <len6> (SE) |
| $\mathrm{Rn}=\operatorname{EXP} \mathrm{Rx}$ |  |
| $\mathrm{Rn}=\mathrm{EXP} \mathrm{Rx}$ (EX) |  |
| $\mathrm{Rn}=\mathrm{LEFTZ} \mathrm{Rx}$ |  |
| $\mathrm{Rn}=\mathrm{LEFTORx}$ |  |

$\mathrm{Rn}, \mathrm{Rx}, \mathrm{Ry} \quad \mathrm{R} 15-\mathrm{R} 0$; register file location, fixed-point
$<$ bit $6>:<l e n 6$ - 6 -bit immediate bit position and length values (for shifter immediate operations)

Table VII. Multifunction Compute Operations

## Fixed-Point

```
Rm=R3-0 * R7-4 (SSFR), Ra=R11-8 + R15-12
Rm=R3-0 * R7-4 (SSFR), Ra=R11-8-R15-12
Rm=R3-0* R7-4 (SSFR), Ra=(R11-8 + R15-12)/2
MRF=MRF + R3-0 * R7-4 (SSF), Ra=R11-8 + R15-12
MRF =MRF + R3-0 * R7-4 (SSF), Ra=R11-8 - R15-12
MRF=MRF + R3-0 * R7-4 (SSF), Ra=(R11-8 + R15-12)/2
Rm=MRF + R3-0 * R7-4 (SSFR), Ra=R11-8 + R15-12
Rm}=\textrm{MRF}+\textrm{R}3-0 * R7-4 (SSFR), Ra=R11-8-R15-12
Rm=MRF + R3-0 * R7-4 (SSFR), Ra=(R11-8 + R15-12)/2
MRF=MRF - R3-0 * R7-4 (SSF), Ra=R11-8 + R15-12
MRF=MRF - R3-0 * R7-4 (SSF), Ra=R11-8-R15-12
MRF=MRF - R3-0 * R7-4(SSF), Ra=(R11-8 + R15-12)/2
Rm=MRF - R3-0 * R7-4 (SSFR), Ra=R11-8 + R15-12
Rm=MRF - R3-0 * R7-4 (SSFR), Ra=R11-8 - R15-12
Rm=MRF - R3-0 * R7-4 (SSFR), Ra=(R11-8 + R15-12)/2
Rm=R3-0 * R7-4 (SSFR), Ra=R11-8 + RI5-12,
                        Rs=R11-8-R15-12
```

Floating-Point
$\mathrm{Fm}=\mathrm{F} 3-0 *$ F7-4, Fa $=\mathrm{F} 11-8+\mathrm{F} 15-12$
$\mathrm{Fm}=\mathrm{F} 3-0 * \mathrm{~F} 7-4, \mathrm{Fa}=\mathrm{F} 11-8-\mathrm{F} 15-12$
$\mathrm{Fm}=\mathrm{F} 3-0 * \mathrm{~F} 7-4, \mathrm{Fa}=\mathrm{FLOAT}$ RII-8 by R15-12
$\mathrm{Fm}=\mathrm{F} 3-0$ * $\mathrm{F} 7-4, \mathrm{Fa}=$ FIX R11-8 by R15-12
$\mathrm{Fm}=\mathrm{F} 3-0 * \mathrm{~F} 7-4, \mathrm{Fa}=(\mathrm{F} 11-8+\mathrm{F} 15-12) / 2$
$\mathrm{Fm}=\mathrm{F} 3-0 * \mathrm{~F} 7-4, \mathrm{Fa}=\mathrm{ABS}$ FI1-8
$\mathrm{Fm}=\mathrm{F} 3-0$ * $\mathrm{F} 7-4, \mathrm{Fa}=\mathrm{MAX}(\mathrm{F} 11-8, \mathrm{~F} 15-12$ )
$\mathrm{Fm}=\mathrm{F} 3-0 * \mathrm{~F} 7-4, \mathrm{Fa}=\mathrm{MIN}(\mathrm{F} 11-8, \mathrm{~F} 15-12)$
$\mathrm{Fm}=\mathrm{F} 3-0 * \mathrm{~F} 7-4, \mathrm{Fa}=\mathrm{F} 11-8+\mathrm{F} 15-12$,
$\mathrm{F}_{s}=\mathrm{F}_{11}-8-\mathrm{F}_{15}-12$
$\mathrm{Ra}, \mathrm{Rm}$ Any register file location (tixed-point)
R3-0 R3, R2, R1, R0
R7-4 R7, R6, R5, R4
R11-8 R11, R10, R9, R8
R15-12 R15, R14, R13, R12
$\mathrm{Fa}, \mathrm{Fm}$ Any register file location (floating-point)
F3-0 F3, F2, F1, F0
F7-4 F7, F6, F5, F4
F11-8 F11, F10, F9, F8
F15-12 F15, F14, F13, F12
(SSF) $\quad \mathrm{X}$-input signed, Y -input signed, fractional inputs
(SSFR) X-input signed, Y-input signed, fractional inputs, rounded output

| Ra, Rm | Any register file location (tixed-point) |
| :--- | :--- |
| R3-0 | R3, R2, R1, R0 |
| R7-4 | R7, R6, R5, R4 |
| R11-8 | R11, R10, R9, R8 |
| R15-12 | R15, R14, R13, R12 |
| Fa, Fm | Any register file location (floating-point) |
| F3-0 | F3, F2, F1, F0 |
| F7-4 | F7, F6, F5, F4 |
| F11-8 | F11, F10, F9, F8 |
| F15-12 | F15, F14, F13, F12 |
| (SSF) | X-input signed, Y-input signed, fractional inputs |
| (SSFR) | X-input signed, Y-input signed, fractional inputs, rounded output |

## ADSP-21020—SPECIFICATIONS

## RECOMMENDED OPERATING CONDITIONS

|  | K Grade |  | B Grade |  | T Grade |  |  |  |
| :--- | :--- | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter |  | Min | Max | Min | Max | Min | Max | Unit |
| $V_{\text {DD }}$ | Supply Voltage | 4.50 | 5.50 | 4.50 | 5.50 | 4.50 | 5.50 | V |
| $\mathrm{T}_{\text {AMB }}$ | Ambient Operating Temperature | 0 | +70 | -40 | +85 | -55 | +125 | ${ }^{\circ} \mathrm{C}$ |

Refer to Environmental Conditions for information on thermal specifications.

## ELECTRICAL CHARACTERISTICS

| Parameter |  | Test Conditions | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {LH }}$ | Hi-Level Input Voltage ${ }^{1}$ | $\mathrm{V}_{\mathrm{DD}}=\max$ | 2.0 |  | V |
| $\mathrm{V}_{\text {IHCR }}$ | Hi-Level Input Voltage ${ }^{2}, 12$ | $\mathrm{V}_{\mathrm{DD}}=\max$ | 3.0 |  | V |
| $\mathrm{V}_{\mathrm{IL}}$ | Lo-Level Input Voltage ${ }^{1,12}$ | $\mathrm{V}_{\mathrm{DD}}=\min$ |  | 0.8 | V |
| $V_{\text {ILC }}$ | Lo-Level Input Voltage ${ }^{2}$ | $\mathrm{V}_{\mathrm{DD}}=\max$ |  | 0.6 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | Hi-Level Output Voltage ${ }^{3,11}$ | $\mathrm{V}_{\mathrm{DD}}=\min , \mathrm{I}_{\mathrm{OH}}=-1.0 \mathrm{~mA}$ | 2.4 |  | V |
| $\mathrm{V}_{\text {OL }}$ | Lo-Level Output Voltage ${ }^{\text {3,11 }}$ | $\mathrm{V}_{\mathrm{DD}}=\mathrm{min}, \mathrm{I}_{\mathrm{OL}}=4.0 \mathrm{~mA}$ |  | 0.4 | V |
| $\mathrm{I}_{\mathrm{IH}}$ | Hi-Level Input Current ${ }^{+5}$ | $\mathrm{V}_{\mathrm{DD}}=\max , \mathrm{V}_{\text {IN }}=\mathrm{V}_{\mathrm{DD}}$ max |  | 10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {IL }}$ | Lo-Level Input Current ${ }^{+}$ | $\mathrm{V}_{\mathrm{DD}}=\max , \mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ |  | 10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {ILT }}$ | Lo-Level Input Current ${ }^{5}$ | $\mathrm{V}_{\mathrm{DD}}=\max , \mathrm{V}_{\mathrm{IN}}=0 \mathrm{~V}$ |  | 350 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {OZH }}$ | Tristate Leakage Current ${ }^{6}$ | $\mathrm{V}_{\mathrm{DD}}=\max , \mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{DD}} \max$ |  | 10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {Ozi }}$ | Tristate Leakage Current ${ }^{6}$ | $\mathrm{V}_{\mathrm{DD}}=\max , \mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ |  | 10 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {DDIN }}$ | Supply Current (Internal) ${ }^{7}$ | $\begin{aligned} & \mathrm{t}_{\mathrm{CK}}=30-33 \mathrm{~ns}, \mathrm{~V}_{\mathrm{DD}}=\max , \mathrm{V}_{\mathrm{IHCR}}=3.0 \mathrm{~V}, \\ & \mathrm{~V}_{\mathrm{IH}}=2.4 \mathrm{~V}, \mathrm{~V}_{\mathrm{IL}}=\mathrm{V}_{\mathrm{ILC}}=0.4 \mathrm{~V} \end{aligned}$ |  | 490 | mA |
| $\mathrm{I}_{\text {doidle }}$ | Supply Current (Idle) ${ }^{8}$ | $\mathrm{V}_{\mathrm{DD}}=\max , \mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ or $\mathrm{V}_{\text {DD }} \max$ |  | 150 | mA |
| $\mathrm{C}_{\text {IN }}$ | Input Capacitance ${ }^{\text {9. }} 10$ | $\mathrm{f}_{\mathrm{IN}}=1 \mathrm{MHz}, \mathrm{T}_{\text {CASE }}=25^{\circ} \mathrm{C}, \mathrm{V}_{\mathrm{IN}}=2.5 \mathrm{~V}$ |  | 10 | pF |

## NOTES

${ }^{1}$ Applies to: PMD47-0, PMACK, $\overline{\text { PMTS }}$, DMD39-0, DMACK, $\overline{\text { DMTS }}, \overline{\text { IRQ }} 3-0$, FLAG3 $-0, \overline{B R}$, TMS, TDI.
${ }^{2}$ Applies to: CLKIN, TCK.
${ }^{3}$ Applies to: PMA23-0, PMD47-0, $\overline{\text { PMS }} 1-0, \overline{\text { PMRD }}, \overline{\text { PMWR }}$, PMPAGE, DMA $31-0$, DMD39-0, $\overline{\text { DMS }} 3-0, \overline{\text { DMRD }}, \overline{\text { DMWR }}$, DMPAGE, FLAG3-0, TIMEXP, BG.
${ }^{4}$ Applies to: PMACK, $\overline{\text { PMTS }}$, DMACK, $\overline{\mathrm{DMTS}}, \overline{\mathrm{IRQ}} 3-0, \overline{\mathrm{BR}}, \mathrm{CLKIN}, \overline{\mathrm{RESET}}, \mathrm{TCK}$.
${ }^{5}$ Applies to: TMS, TDI, TRST.
${ }^{6}$ Applies to: PMA23-0, PMD $47-0, \overline{\text { PMS }} 1-0, \overline{\text { PMRD }}, \overline{\text { PMWR }}$, PMPAGE, DMA31-0, DMD39-0, $\overline{\mathrm{DMS}} 3-0, \overline{\text { DMRD }}, \overline{\mathrm{DMWR}}$, DMPAGE, FLAG3-0, TDO.
${ }^{7}$ Appplies to IVDD pins. At $\mathrm{t}_{\mathrm{CK}}=30-33 \mathrm{~ns}, \mathrm{I}_{\text {DDIN }}$ (typical) $=230 \mathrm{~mA}$; at $\mathrm{t}_{\mathrm{CK}}=40 \mathrm{~ns}, \mathrm{I}_{\mathrm{DDIN}}(\max )=420 \mathrm{~mA}$ and $\mathrm{I}_{\text {DDIN }}$ (typicai) $=200 \mathrm{~mA}$; at $\mathrm{t}_{\mathrm{CK}}=50 \mathrm{~ns}$,
$\mathrm{I}_{\text {DDIN }}(\max )=370 \mathrm{~mA}$ and $\mathrm{I}_{\text {DDIN }}$ (typical) $=115 \mathrm{~mA}$. See "Power Dissipation" for calculation of external (EVDD) supply current for total supply current.
${ }^{8}$ Applies to IVDD pins. Idle refers to ADSP-21020 state of operation during execution of the IDLE instruction.
${ }^{9}$ Guaranteed but not tested.
${ }^{10}$ Applies to all signal pins.
"Although specified for TTL outputs, all ADSP- 21020 outputs are CMOS-compatible and will drive to $\mathrm{V}_{\mathrm{DD}}$ and GND assuming no dc loads.
${ }^{12}$ Applies to RESET, TRST.

## ABSOLUTE MAXIMUM RATINGS*

| Supply Voltage | 3 V to +7 V |
| :---: | :---: |
| Input Voltage | -0.3 V to $\mathrm{V}_{\mathrm{DD}}+0.3 \mathrm{~V}$ |
| Output Voltage Swing | -0.3 V to $\mathrm{V}_{\mathrm{DD}}+0.3 \mathrm{~V}$ |
| Load Capacitance | 200 pF |
| Operating Temperature Range (Ambient) | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ |
| Storage Temperature Range | $65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
|  | $+300^{\circ}$ |

*Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## ESD SENSITIVITY

The ADSP-21020 features proprietary input protection circuitry to dissipate high-energy discharges (Human Body Model). Per method 3015 of MIL-STD-883, the ADSP-21020 has been classified as a Class 3 device, with the ability to withstand up to 4000 V ESD.
Proper ESD precautions are strongly recommended to avoid funcrional damage or performance degradation. Charges readily accumulate on the human body and test equipment and discharge without detection. Lnused devices must be stored in conductive foam or shunts, and the foam
 should be discharged to the destination socket before devices are removed. For further information on ESD precautions, refer to Analog Devices' ESD Prevention .Hamul.

## TIMING PARAMETERS

## General Notes

See Figure 15 on page 24 for voltage reference levels. Use the exact timing information given. Do not attempt to derive parameters from the addition or subtraction of others. While addition or subtraction would yield meaningful results for an individual device, the values given in this data sheet reflect statistical variations and worst cases. Consequently, you cannot meaningfully add parameters to derive other specifications.

## Clock Signal

| Parameter |  | K/B/T Grade |  | K/B/T Grade |  | B/T Grade |  | K Grade |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | 20 MHz |  | 25 MHz |  | 30 MHz |  | 33.3 MHz |  | Unit |
|  |  | Min | Max | Min | Max | Min | Max | Min | Max |  |
| Timing Requirement: |  |  |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{CK}}$ | CLKIN Period | 50 | 150 | 40 | 150 |  | 150 | 30 | 150 | ns |
| ${ }_{\text {cker }}$ | CLKIN Width High | 10 |  | 10 |  | 10 |  | 10 |  | ns |
| $\mathrm{t}_{\mathrm{CKL}}$ | CLKIN Width Low | 10 |  | 10 |  | 10 |  | 10 |  | ns |



Figure 3. Clock

## Reset

|  | K/B/T Grade |  | K/B/T Grade |  | B/T Grade |  | K Grade |  | Frequency Dependency* <br> Min <br> Max |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter | $\begin{array}{r} 20 \\ \mathrm{Min} \end{array}$ | MHz <br> Max | $\begin{array}{r} 25 \\ \mathrm{Min} \end{array}$ | $\begin{aligned} & \mathrm{MHz} \\ & \mathrm{Max} \end{aligned}$ | $\begin{array}{r} 30 \\ \mathrm{Min} \end{array}$ | MHz <br> Max |  | $\begin{gathered} \mathrm{MHz} \\ \mathrm{Max} \end{gathered}$ |  |  |  |
| Timing Requirement: <br> $\mathrm{t}_{\text {WRST }}{ }^{1}$ RESET Width Low <br> $\mathrm{t}_{\text {SRST }}{ }^{2}$ RESET Setup before CLKIN High | $\begin{aligned} & 200 \\ & 29 \end{aligned}$ | 50 | $\begin{aligned} & 160 \\ & 24 \end{aligned}$ | 40 | $\begin{array}{\|l} 132 \\ 21 \end{array}$ | 33 |  |  | $\begin{aligned} & 4 \mathrm{t}_{\mathrm{CK}} \\ & 29+\mathrm{DT} / 2 \end{aligned}$ | 30 | $\left\lvert\, \begin{aligned} & \text { ns } \\ & \text { ns } \end{aligned}\right.$ |

## NOTES

${ }^{* D T}=\mathrm{t}_{\mathrm{ck}}-50 \mathrm{~ns}$
${ }^{1}$ Applies after the power-up sequence is complete. At power up, the Internal Phase Locked Loop requires no more than 1000 CLKIN cycles while RESET is low, assuming stable $\mathrm{V}_{\mathrm{DD}}$ and CLKIN (not including clock oscillator start-up time).
${ }^{2}$ Specification only applies in cases where multiple ADSP-21020 processors are required to execute in program counter lock-step (all processors start execution at location 8 in the same cycle). See the Hardware Configuration chapter of the ADSP-21020 User's Manual for reset sequence information.


Figure 4. Reset

## ADSP-21020

Interrupts

|  | K/B/T Grade |  | K/B/T Grade |  | B/T Grade |  | K Grade |  | Frequency Dependency* <br> Min Max |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter | $\begin{array}{r} 20 \\ \operatorname{Min} \end{array}$ | MHz <br> Max | $\begin{array}{r} 25 \\ \mathrm{Min} \end{array}$ | MHz <br> Max | $\begin{array}{r} 30 \\ \mathrm{Min} \end{array}$ | MHz <br> Max |  | $\mathrm{MHz}$ Max |  |  |  |
| Timing Requirement: |  |  |  |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\text {SIR }}$ $\overline{\text { IRQ3-0 }}$ Setup before CLKIN High <br> $\mathrm{t}_{\text {HIR }} \overline{\text { IRQ3-0 }}$ Hold after CLKIN High  <br> $\mathrm{t}_{\text {IPW }}$ IRQ3-0 Pulse Width | 38 0 55 |  | $\begin{aligned} & 31 \\ & 0 \\ & 45 \end{aligned}$ |  | $\begin{aligned} & 25 \\ & 0 \\ & 38 \end{aligned}$ |  | $\begin{aligned} & 23 \\ & 0 \\ & 35 \end{aligned}$ |  | $\begin{aligned} & 38+3 \mathrm{DT} / 4 \\ & \mathrm{t}_{\mathrm{CK}}+5 \end{aligned}$ |  | ns ns ns |

NOTE
*DT $=\mathrm{t}_{\mathrm{CK}}-50 \mathrm{~ns}$
Meeting setup and hold guarantees interrupts will be latched in that cycle. Meeting the puise width is not necessary if the setup and hold is met. Likewise, meeting the setup and hold is not necessary if the pulse width is met. See the Hardware Contiguration chapter of the ADSP-21020 User's Manual for interrupt servicing information.


Figure 5. Interrupts

Timer

|  | K/B/T Grade |  | K/B/T Grade |  | B/T Grade |  | K Grade |  | $\begin{aligned} & \text { Frequency Dependency* } \\ & \text { Min } \quad \text { Max } \end{aligned}$ |  | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter | $\underset{\mathrm{Min}}{20}$ | MHz <br> Max | $\begin{array}{r} 25 \\ \mathrm{Min} \end{array}$ | $\mathbf{4 H z}$ Max | $\begin{gathered} 30 \\ \mathrm{Min} \end{gathered}$ | $\begin{aligned} & \mathbf{M H z} \\ & \mathbf{M a x} \end{aligned}$ |  | $\mathbf{M H z}$ <br> Max |  |  |  |
| Switching Characteristic: <br> $t_{\text {dex }}$ CLKIN High to TIMEXP |  | 24 |  | 24 |  | 24 |  | 24 |  |  | ns |

NOTE
${ }^{*} \mathrm{DT}=\mathrm{L}_{\mathrm{Cx}}-50 \mathrm{~ns}$


Figure 6. TIMEXP

Flags

|  | K/B/T Grade |  | K/B/T Grade |  | B/T Grade |  | K Grade |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter | $\begin{gathered} 20 \\ \operatorname{Min} \end{gathered}$ | M $\mathrm{Hz}{ }_{\text {a }}$ Max | 25 MHz |  | 30 MHz |  | 33.3 MHz |  | $\begin{aligned} & \text { Frequency Dependency* } \\ & \text { Min } \quad \text { Max } \end{aligned}$ |  | Unit |
| Timing Requirement: ${ }^{\text {I }}$ |  |  |  |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\text {SFI }} \quad$ FLAG3-0 ${ }_{\text {IN }}$ Serup before CLKIN High | 19 |  | 16 |  | 14 |  | 13 |  | $19+5$ |  | ns |
| $\mathrm{t}_{\mathrm{HFI}} \quad$ FLAG3-0 ${ }_{\text {IN }}$ Hold after CLKIN High |  |  |  |  |  |  |  |  |  |  | ns |
| $\mathrm{t}_{\text {DWRFI }}$ FLAG3-0 $0_{\text {IN }}$ Delay from $\overline{\text { xRD }}$, $\overline{\mathrm{xWR}}$ Low |  | 12 |  | 8 |  | 5 |  | 3 |  | 12-7DT/16 | ns |
| $\mathrm{t}_{\text {HFIWR }}$ FLAG3-0 $0_{\text {IN }}$ Hold after $\overline{\mathrm{xRD}}, \overline{\mathrm{xWR}}$ Deasserted | 0 |  | 0 |  | 0 |  | 0 |  |  |  | ns |
| Switching Characteristic: |  |  |  |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\text {dFo }}$ FLAG3-0 ${ }_{\text {Out }}$ Delay from CLKIN High |  | 24 |  | 24 |  | 24 |  | 24 |  |  | ns |
| $\mathrm{t}_{\mathrm{HFO}}$ FLAG3-0 ${ }_{\text {OUT }}$ Hold after CLKIN High | 5 |  | S |  | 5 |  | 5 |  |  |  | ns |
| $t_{\text {dFoe }}$ CLKIN High to FLAG3-0 ${ }_{\text {OLT }}$ Enable | 1 |  | 1 |  | 1 |  |  |  |  |  | ns |
| $\mathrm{t}_{\text {DFOD }}$ CLKIN High to FLAG3-0 ${ }_{\text {OLT }}$ Disable |  | $2+$ |  | 24 |  | 24 |  | 24 |  |  | ns |

NOTES
*DT $=\mathrm{t}_{\mathrm{Cx}}-50 \mathrm{~ns}$
${ }^{1}$ Flag inputs meeting these setup and hold times will affect conditional operations in the next instruction cycle. See the Hardware Configuration chapter of the ADSP-21020 User's Manual for additional flag servicing information.
$\mathrm{x}=\mathrm{PM}$ or DM .


Figure 7. Flags

## ADSP-21020

Bus Request/Bus Grant


NOTES
${ }^{*} D T=\tau_{C K}-50 \mathrm{~ns}$.
Memory Interface $=$ PMA23-0, PMD47-0, $\overline{\text { PMS1-0 }}, \overline{\text { PMRD }}, \overline{\text { PMWR }}$, PMPAGE, DMA31-0, DMD39-0, $\overline{\text { DMS3-0 }}, \overline{\text { DMRD }}, \overline{\text { DMWR }}, ~ D M P A G E$.
Buses are not granted until completion of current memory access.
See the Memory Interface chapter of the $A D S P-21020$ User's Manual for $\overline{\mathrm{BG}}, \overline{\mathrm{BR}}$ cycle relationships.


Figure 8. Bus Request/Bus Grant

## External Memory Three-State Control

|  | K/B/T Grade |  | K/B/T Grade |  | B/T Grade |  | K Grade |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter | 20 MHz |  | $\underset{\text { Min }}{25}$ | MHz Max | 30 MHz |  | 33.3 MHz |  | Frequency Dependency* <br> Min Max |  | Unit |
| Timing Requirement: |  |  |  |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\text {STS }}$ XTS , Setup before CLKIN High | 14 | 50 | 12 | 40 | 10 | 33 |  | 30 | 14 + DT/4 | $\mathrm{t}_{\mathrm{CK}}$ | ns |
| $\mathrm{t}_{\text {Dadts }}$ xTS Delay after Address, Select |  | 28 |  | 19 |  | 13 |  | 10 |  | $28+7 \mathrm{DT} / 8$ | ns |
| $\mathrm{t}_{\text {DSTS }} \overline{\mathrm{XTS}}$ Delay after XRD, XWR Low |  | 16 |  | 11 |  | 7 |  | 6 |  | $16+\mathrm{DT} / 2$ | ns |
| Switching Characteristic: |  |  |  |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\text {DTSD }}$ Memory Interface Disable before CLKIN High | 0 |  | -2 |  | -4 |  | -5 |  | DT/4 |  | ns |
| $\mathrm{t}_{\text {dtSae }} \overline{\mathrm{xTS}}$ High to Address, Select Enable | - |  | 0 |  | 0 |  | 0 |  |  |  | ns |

## NOTES

${ }^{* D T}=\mathrm{t}_{\mathrm{CK}}-50 \mathrm{~ns}$
Memory Interface $=$ PMA23-0, PMD47-0, $\overline{\text { PMSI-0 }}, \overline{\text { PMRD }}, \overline{\text { PMWR }}$, PMPAGE, DMA31-0, DMD39-0, $\overline{\text { DMS3-0 }}, \overline{\text { DMRD }}, \overline{\text { DMWR }}$, DMPAGE. Address $=$ PMA23-0, DMA31-0. Select $=\overline{\text { PMS1-0 }}, \overline{\text { DMS3-0 }}$.
$\mathrm{x}=\mathrm{PM}$ or DM .


Figure 9. External Memory Three-State Control

ADSP-21020
Memory Read

|  | K/B/T Grade |  | K/B/T Grade |  | B/T Grade |  | K Grade |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter | $\begin{array}{r} 20 \\ \mathrm{Min} \end{array}$ | MHz <br> Max | $\begin{array}{r} 25 \\ \operatorname{Min} \end{array}$ | MHz <br> Max | $\begin{array}{r} 30 \\ \mathrm{Min} \end{array}$ | MHz <br> Max |  | $\begin{gathered} \text { MHz } \\ \text { Max } \end{gathered}$ | Frequency D Min | Dependence* <br> Max | Unit |
| Timing Requirement: |  |  |  |  |  |  |  |  |  |  |  |
| $\mathrm{t}_{\text {Dad }}$ Address, Select to Data Valid |  | 37 |  | 27 |  | 20 |  | 17 |  | $37+$ DT | ns |
| $\mathrm{t}_{\text {DRLD }} \overline{\mathrm{xRD}}$ Low to Data Valid |  | 24 |  | 18 |  | 13 |  | 11 |  | $24+5 \mathrm{DT} / 8$ | ns |
| $\mathrm{t}_{\text {HDA }}$ Data Hold from Address, Select | 0 |  | 0 |  | 0 |  | 0 |  |  |  | ns |
| $t_{\text {HDRH }}$ Data Hold from $\overline{\text { xRD High }}$ | -1 |  | -1 |  | -1 |  | -1 |  |  |  | ns |
| $\mathrm{t}_{\text {DAAK }}$ xACK Delay from Address |  | 27 |  | 18 |  | 12 |  | 9 |  | $27+7 \mathrm{DT} / 8$ | ns |
| $\mathrm{t}_{\text {DRAK }}$ xACK Delay from $\overline{\mathrm{xRD}}$ Low |  | 15 |  | 10 |  | 6 |  | 5 |  | $15+\mathrm{DT} / 2$ | ns |
| $\mathrm{t}_{\text {SAK }} \quad$ xACK Setup before CLKIN High | 14 |  | 12 |  | 10 |  | 9 |  | $14+\mathrm{DT} / 4$ |  | ns |
| $\mathrm{t}_{\text {HAK }} \quad$ xACK Hold after CLKIN High | 0 |  | 0 |  | 0 |  | 0 |  |  |  | ns |
| Switching Characteristic: |  |  |  |  |  |  |  |  |  |  |  |
| $t_{\text {Darl }}$ Address, Select to $\overline{x R D}$ Low | 8 |  | 4 |  | 2 |  | 0 |  | $8+3 \mathrm{DT} / 8$ |  | ns |
| $\mathrm{t}_{\text {DAP }} \quad$ xPAGE Delay from Address, Select |  | 1 |  | 1 |  | 22 |  | 1 |  |  | ns |
| $t_{\text {dckrl }}$ CLKIN High to $\overline{\text { xRD }}$ Low | 16 | 26 | 13 | 24 | 12 | 22 |  | 21 | $16+$ DT/4 | $26+$ DT/4 | ns |
| $\mathrm{t}_{\text {RW }} \quad$ xRD Pulse Width | 26 |  | 20 |  | 15 |  | 13 |  | $26+5 \mathrm{DT} / 8$ |  | ns |
| $\mathrm{t}_{\text {RwR }}$ xRD High to $\overline{\mathrm{xRD}}$, $\overline{\mathrm{xWR}}$ Low | 17 |  | 13 |  | 11 |  | 9 |  | $17+3 \mathrm{DT} / 8$ |  | ns |

NOTES
$* D T=\mathrm{t}_{\mathrm{CK}}-50 \mathrm{~ns}$



Figure 10. Memory Read

ADSP-21020
Memory Write


## NOTES

*DT $=\mathrm{t}_{\mathrm{c}}-50 \mathrm{~ns}$
'See "System Hold Time Calculation" in "Test Conditions" secrion for calculating hold times given capacitive and DC loads.
$\mathrm{x}=\mathrm{PM}$ or DM; Address $=$ PMA23-0, DMA31-0; Data $=$ PMD47-0, DMD39-0; Select $=\overline{\text { PMS1-0 }}, \overline{\mathrm{DMS}}$-0 .


Figure 11. Memory Write

IEEE 1149.1 Test Access Port


NOTES
${ }^{*} \mathrm{DT}=\mathrm{t}_{\mathrm{CK}}-50 \mathrm{~ns}$
System Inpurs $=$ PMD47-0, PMACK, $\overline{\text { PMTS }}$, DMD39-0, DMACK, $\overline{\text { DMTS }}$, CLKIN, $\overline{\text { IRQ3-0 }}, \overline{\text { RESET }}$, FLAG3-0. $\overline{\text { BR }}$.
System Outputs $=$ PMA23-0, $\overline{\text { PMSI-0 }}, \overline{\text { PMRD }}, \overline{\text { PMWR }}$, PMD47-0, PMPAGE, DMA31-0, $\overline{\text { DMSI-0 }}, \overline{\text { DMRD }}, \overline{\text { DMWR }}$, DMD39-0, DMPAGE, FLAG3-0, $\overline{\mathrm{BG}}$, TIMEXP.
See the IEEE 1149.1 Test Access Port chapter of the ADSP-21020 User's Manual for further detail.


Figure 12. IEEE 1149.1 Test Access Port

## ADSP-21020

## TEST CONDITIONS

## Output Disable Time

Output pins are considered to be disabled when they stop driving, go into a high-impedance state, and start to decay from their output high or low voltage. The time for the voltage on the bus to decay by $\Delta \mathrm{V}$ is dependent on the capacitive load, $\mathrm{C}_{\mathrm{L}}$, and the load current, $\mathrm{I}_{\mathrm{L}}$. It can be approximated by the following equation:

$$
t_{D E C A Y}=\frac{C_{L} \Delta V}{I_{L}}
$$

The output disable time ( $t_{\text {DIS }}$ ) is the difference between $\mathrm{t}_{\text {meastired }}$ and $\mathrm{t}_{\text {decay }}$ as shown in Figure 13. The time $t_{\text {measured }}$ is the interval from when the reference signal switches to when the output voltage decays $\bar{V}$ from the measured output high or output low voltage. $t_{\text {DECAY }}$ is calculated with $د \mathrm{~V}$ equal to 0.5 V , and test loads $\mathrm{C}_{\mathrm{L}}$ and $\mathrm{I}_{\mathrm{L}}$.

## Output Enable Time

Output pins are considered to be enabled when they have made a transition from a high-impedance state to when they start driving. The output enable time ( $\mathrm{t}_{\mathrm{ENA}}$ ) is the interval from when a reference signal reaches a high or low voltage level to when the output has reached a specified high or low trip point, as shown in the Output Enable/Disable diagram. If multiple pins (such as the data bus) are enabled, the measurement value is that of the first pin to start driving.

## Example System Hold Time Calculation

To determine the data output hold time in a particular system, first calculate $t_{\text {Decay }}$ using the above equation. Choose $\Delta V$ to be the difference between the ADSP-21020's output voltage and the input threshold for the device requiring the hold time. A typical $\Delta \mathrm{V}$ will be $0.4 \mathrm{~V} . \mathrm{C}_{\mathrm{L}}$ is the total bus capacitance (per data line), and $\mathrm{I}_{\mathrm{L}}$ is the total leakage or three-state current (per data line). The hold time will be $t_{\text {decay }}$ plus the minimum disable time (i.e. $\mathrm{t}_{\mathrm{HDwD}}$ for the write cycle).

*AC TIMING SPECIFICATIONS ARE CALCULATED FOR 100pF DERATING ON THE FOLLOWING PINS: PMA23-0, PMS1-0. $\overline{\text { PMRD }}$, PMWF, PMPAGE, DMA31-0, DMS3-0, DMRD, DMWR, DMPAGE

Figure 14. Equivalent Device Loading For AC Measurements (Includes All Fixtures)


Figure 15. Voltage Reference Levels For AC Measurements (Except Output Enable/Disable)


Figure 13. Output Enable/Disable

## Capacitive Loading

Output delays are based on standard capacitive loads: 100 pF on address, select, page and strobe pins, and 50 pF on all others (see Figure 14). For different loads, these timing parameters should be derated. See the Hardware Configuration chapter of the ADSP-21020 User's Manual for further information on derating of timing specifications.
Figures 16 and 17 show how the output rise time varies with capacitance. Figures 18 and 19 show how output delays vary with capacitance. Note that the graphs may not be linear outside the ranges shown.


NOTES:
(1) OUTPUT PINS $\overline{\text { BG. TIMEXP }}$
(2) OUTPUT PINS PMD47-0, DMD39-0, FLAG3-0

Figure 16. Typical Output Rise Time vs. Load Capacitance (at Maximum Case Temperature)


NOTES:
(1) OUTPUT PINS PMA23-0. $\overline{\text { PMS1-0 }}$, PMPAGE, DMA31-0, $\overline{\text { DMS3-0 }}$, OMPAGE, TDO (2) OUTPUT PINS PMRD, $\overline{\text { PMWR }}, \overline{D M R D}$. DMWR

Figure 17. Typical Output Rise Time vs. Load Capacitance (at Maximum Case Temperature)


Figure 18. Typical Output Delay or Hold vs. Load Capacitance (at Maximum Case Temperature)


NOTES:
(1) OUTPUT PINS PMA23-0, $\overline{\text { PMS1-0 }}$, PMPAGE, DMA31-0, DMS3-0. DMPAGE, TDO (2) OUTPUT PINS $\overline{\text { PMRD }}, \overrightarrow{\text { PMWR }}, \overline{D M R D}, \overline{D M W R ~}$

Figure 19. Typical Output Delay or Hold vs. Load Capacitance (at Maximum Case Temperature)

## ENVIRONMENTAL CONDITIONS

The ADSP-21020 is available in a Ceramic Pin Grid Array (CPGA). The package uses a cavity-down configuration which gives it favorable thermal characteristics. The top surface of the package contains a raised copper slug from which much of the die heat is dissipated. The slug provides a surface for mounting a heat sink (if required).
The commercial grade ( K grade) ADSP-21020 is specified for operation at $\mathrm{T}_{\mathrm{AMB}}$ of $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$. Maximum $\mathrm{T}_{\text {CASE }}$ (case temperature) can be calculated from the following equation:

$$
T_{C A S E}=T_{A M B}+\left(P D \times \theta_{C A}\right)
$$

where PD is power dissipation and $\theta_{C A}$ is the case-to-ambient thermal resistance. The value of PD depends on your application; the method for calculating PD is shown under "Power Dissipation" below. $\theta_{\mathrm{CA}}$ varies with airflow and with the presence or absence of a heat sink. Table IX shows a range of $\theta_{C A}$ values.

## Table IX. Maximum $\boldsymbol{\theta}_{\mathrm{CA}}$ for Various Airflow Values

| Airflow (Linear ft./min.) | 0 | 100 | 200 | 300 |
| :--- | :--- | :--- | :--- | :--- |
| CPGA with No Hear Sink | $12.8^{\circ} \mathrm{C} / \mathrm{W}$ | $9.2^{\circ} \mathrm{C} / \mathrm{W}$ | $6.6^{\circ} \mathrm{C} / \mathrm{W}$ | $5.5^{\circ} \mathrm{C} / \mathrm{W}$ |

## NOTE

As per method 1012 MIL-STD-883. Ambient temperature: $25^{\circ} \mathrm{C}$. Power: 3.5 W .

## Power Dissipation

Total power dissipation has two components: one due to internal circuitry and one due to the switching of external output drivers. Internal power dissipation is dependent on the instruction execution sequence and the data values involved. Internal power dissipation is calculated in the following way:

$$
\mathrm{P}_{\mathrm{INT}}=\mathrm{I}_{\mathrm{DDIN}} \times \mathrm{V}_{\mathrm{DD}}
$$

The external component of total power dissipation is caused by the switching of output pins. Its magnitude depends on:

1) the number of output pins that switch during each cycle (O),
2) the maximum frequency at which they can switch (f),
3) their load capacitance ( $C$ ), and
4) their voltage swing ( $\mathrm{V}_{\mathrm{DD}}$ ).

It is calculated by:

$$
\mathrm{P}_{\mathrm{EXT}}=\mathrm{O} \times \mathrm{C} \times \mathrm{V}_{\mathrm{DD}}^{2} \times \mathrm{f}
$$

The load capacitance should include the processor's package capacitance $\left(\mathrm{C}_{\mathrm{iN}}\right)$. The switching frequency includes driving the load high and then back low. Address and data pins can drive high and low at a maximum rate of $1 /\left(2 \mathrm{t}_{\mathrm{CK}}\right)$. The write strobes can switch every cycle at a frequency of $1 / t_{\mathrm{CK}}$. Select pins switch at $1 /\left(2 t_{\text {CK }}\right)$, but 2 DM and 2 PM selects can switch on each cycle. If only one bank is accessed, no select line will switch.

## Example:

Estimate $\mathrm{P}_{\mathrm{EXT}}$ with the following assumptions:

- A system with one RAM bank each of PM ( 48 bits) and DM (32 bits).
- $32 \mathrm{~K} \times 8$ RAM chips are used, each with a load of 10 pF .
- Single-precision mode is enabled so that only 32 data pins can switch at once.
- PM and DM writes occur every other cycle, with $50 \%$ of the pins switching.
- The instruction cycle rate is $20 \mathrm{MHz}\left(\mathrm{t}_{\mathrm{CK}}=50 \mathrm{~ns}\right)$ and $\mathrm{V}_{\mathrm{DD}}=5.0 \mathrm{~V}$.
The $P_{\text {EXT }}$ equation is calculated for each class of pins that can drive:

| Pin <br> Type | $\#$ <br> Pins | $\%$ <br> Switch | $\times \mathrm{C}$ | $\times \mathbf{f}$ | $\times \mathrm{V}_{\text {DD }}{ }^{2}$ | P $_{\text {EXT }}$ |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| PMA | 15 | 50 | 68 pF | 5 MHz | 25 V | 0.064 W |
| PMS | 2 | 0 | 68 pF | 5 MHz | 25 V | 0.000 W |
| PMWR | 1 | - | 68 pF | 10 MHz | 25 V | 0.017 W |
| PMD | 32 | 50 | 18 pF | 5 MHz | 25 V | 0.036 W |
| DMA | 15 | 50 | 48 pF | 5 MHz | 25 V | 0.045 W |
| $\overline{\text { DMS }}$ | 2 | 0 | 48 pF | 5 MHz | 25 V | 0.000 W |
| $\overline{\text { DMWR }}$ | 1 | - | 48 pF | 10 MHz | 25 V | 0.012 W |
| DMD | 32 | 50 | 18 pF | 5 MHz | 25 V | 0.036 W |
| $\mathrm{P}_{\text {EXT }}=0.210 \mathrm{~W}$ |  |  |  |  |  |  |

A typical power consumption can now be calculated for this situation by adding a typical internal power dissipation:

$$
\begin{aligned}
P_{\text {TOTAL }} & =P_{\text {EXT }}+\left(5 \mathrm{~V} \times \mathrm{I}_{\text {DDIN }}(\text { typ })\right)=0.210+1.15 \\
& =1.36 \mathrm{~W}
\end{aligned}
$$

Note that the conditions causing a worst case $\mathrm{P}_{\text {EXT }}$ are different from those causing a worst case $P_{\mathrm{INT}}$. Maximum $\mathrm{P}_{\mathrm{INT}}$ cannot occur while $100 \%$ of the output pins are switching from all ones to all zeros. Also note that it is not common for a program to have $100 \%$ or even $50 \%$ of the outputs switching simultaneously.

## Power and Ground Guidelines

To achieve its fast cycle time, including instruction fetch, data access, and execution, the ADSP-21020 is designed with high speed drivers on all output pins. Large peak currents may pass through a circuit board's ground and power lines, especially when many output drivers are simultaneously charging or discharging their load capacitances. These transient currents can cause disturbances on the power and ground lines. To minimize these effects, the ADSP-21020 provides separate supply pins for its internal logic (IGND and IVDD) and for its external drivers (EGND and EVDD).
To reduce system noise at low temperatures when transistors switch fastest, the ADSP-21020 employs compensated output drivers. These drivers equalize slew rate over temperature extremes and process variations. A $1.8 \mathrm{k} \Omega$ resistor placed between the RCOMP pin and EVDD $(+5 \mathrm{~V})$ provides a reference for the compensated drivers. Use of a capacitor (approximately 100 pF ), placed in parallel with the $1.8 \mathrm{k} \Omega$ resistor, is recommended.

All GND pins should have a low impedance path to ground. A ground plane is required in ADSP-21020 systems to reduce this impedance, minimizing noise.

The EVDD and IVDD pins should be bypassed to the ground plane using approximately $1+$ high-frequency capacitors $(0.1 \mu \mathrm{~F}$ ceramic). Keep each capacitor's lead and trace length to the pins as short as possible. This low inductive path provides the ADSP-21020 with the peak currents required when its outpur drivers switch. The capacitors' ground leads should also be short and connect directly to the ground plane. This provides a low
impedance return path for the load capacitance of the ADSP21020's output drivers.
If a $V_{D D}$ plane is not used, the following recommendations apply. Traces from the +5 V supply to the 10 EVDD pins should be designed to satisfy the minimum $\mathrm{V}_{\mathrm{DD}}$ specification while carrying average dc currents of [ $\mathrm{I}_{\text {DDEX }} / 10 \times$ (number of EVDD pins per trace)]. $I_{\text {DDEX }}$ is the calculated external supply current. A similar calculation should be made for the four IVDD pins using the $I_{\text {DDIN }}$ specification. The traces connecting +5 V to the IVDD pins should be separate from those connecring to the EVDD pins.
A low frequency bypass capacitor $20 \mu \mathrm{~F}$ tantalum) located near the junction of the IVDD and EVDD traces is also recommended.

## Target System Requirements For Use Of EZ-ICE Emulator

 The ADSP-21020 EZ-ICE uses the IEEE 1149.1 JTAG test access port of the ADSP-21020 to monitor and control the target board processor during emulation. The EZ-ICE probe requires that CLKIN, TMS, TCK, TRST, TDI, TDO, and GND be made accessible on the target system via a 12-pin connector (pin strip header) such as that shown in Figure 20. The EZ-ICE probe plugs directly onto this connector for chip-on-board emulation; you must add this connector to your target board design if you intend to use the ADSP-21020 EZ-ICE. Figure 21 shows the dimensions of the EZ-ICE probe; be sure to allow enough space in your system to fit the probe onto the 12 -pin connector.

Figure 20. Target Board Connector for EZ-ICE Emulator (Jumpers in Place)


Figure 21. EZ-ICE Probe

The 12 -pin, 2 -row pin strip header is keyed at the Pin 1 location -you must clip Pin I off of the header. The pins must be 0.025 inch square and at least 0.20 inch in length. Pin spacing is $0.1 \times 0.1$ inches.

The tip of the pins must be at least 0.10 inch higher than the tallest component under the probe to allow clearance for the bottom of the probe. Pin strip headers are available from vendors such as 3 M , McKenzie, and Samtec.
The length of the traces between the EZ-ICE probe connector and the ADSP-21020 test access port pins should be less than 1 inch. Note that the EZ-ICE probe adds two TTL loads to the CLKIN pin of the ADSP-21020.
The BMTS, BTCK, $\overline{\text { BTRST, and BTDI signals are provided so }}$ that the test access port can also be used for board-level testing. When the connector is not being used for emulation, place jumpers berween the BXXX pins and the XXX pins as shown in Figure 20. If you are not going to use the test access port for board test, tie BTRST to GND and tie or pull up BTCK to VDD. The TRST pin must be asserted (pulsed low) after power up (through $\overline{\mathrm{BTRST}}$ on the connector) or held low for proper operation of the ADSP- 21020 .



ADSP-21020

| PGA <br> LOCATION | PIN NAME | PGA <br> LOCATION | PIN NAME | PGA <br> LOCATION | PIN NAME | PGA <br> LOCATION | PIN NAME |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| G16 | DMAO | B5 | DMD25 | K1 | PMD9 | L16 | TIMEXP |
| G17 | DMA1 | B6 | DMD26 | 13 | PMD10 | U12 | RCOMP |
| F18 | DMA2 | D6 | DMD27 | L2 | PMD11 | T11 | CLKIN |
| F17 | DMA3 | C6 | DMD28 | M1 | PMD12 | T14 | TRST |
| F16 | DMA4 | A8 | DMD29 | M2 | PMD13 | R12 | TDO |
| F15 | DMA5 | C7 | DMD30 | M3 | PMD14 | S13 | TDI |
| E18 | DMA6 | D7 | DMD31 | M4 | PMD15 | U16 | TMS |
| E17 | DMA7 | B7 | DMD32 | N2 | PMD16 | U14 | TCK |
| E16 | DMA8 | B8 | DMD33 | N3 | PMD17 | H18 | EGND |
| D18 | DMA9 | A10 | DMD34 | P1 | PMD18 | A3 | EGND |
| E15 | DMA 10 | C 8 | DMD35 | P2 | PMD19 | A7 | EGND |
| D17 | DMA11 | D8 | DMD36 | N4 | PMD20 | A11 | EGND |
| D16 | DMA12 | B9 | DMD37 | S1 | PMD21 | A15 | EGND |
| C18 | DMA 13 | C9 | DMD38 | P3 | PMD22 | E1 | EGND |
| C17 | DMA14 | B10 | DMD39 | R2 | PMD23 | G1 | EGND |
| D15 | DMA 15 | D10 | DMS0 | P4 | PMD24 | L1 | EGND |
| B18 | DMA16 | C11 | DMS 1 | R3 | PMD25 | L18 | EGND |
| B17 | DMA17 | A12 | $\overline{\text { DMS2 }}$ | S2 | PMD26 | R1 | EGND |
| C16 | DMA18 | B11 | DMS3 | T1 | PMD27 | R18 | EGND |
| D14 | DMA19 | T13 | DMWR | S3 | PMD28 | T18 | EGND |
| C15 | DMA20 | S11 | DMRD | R4 | PMD29 | U5 | EGND |
| B16 | DMA21 | B12 | DMPAGE | T2 | PMD30 | U7 | EGND |
| A16 | DMA22 | S12 | $\overline{\text { DMTS }}$ | U1 | PMD31 | U11 | EGND |
| D13 | DMA23 | T12 | DMACK | T3 | PMD32 | U15 | EGND |
| C14 | DMA24 | L17 | PMAO | R5 | PMD33 | D11 | IGND |
| B15 | DMA25 | M18 | PMA1 | S4 | PMD34 | G4 | IGND |
| B14 | DMA26 | M15 | PMA2 | U2 | PMD35 | G15 | IGND |
| D12 | DMA27 | M16 | PMA3 | S5 | PMD36 | 14 | IGND |
| C13 | DMA28 | M17 | PMA4 | T4 | PMD37 | L15 | IGND |
| A14 | DMA29 | N17. | PMA5 | R6 | PMD38 | R7 | IGND |
| B13 | DMA30 | N16 | PMA6 | U3 | PMD39 | R11 | IGND |
| C12 | DMA31 | N15. | PMA7 | U4 | PMD40 | A5 | EVDD |
| H3 | DMD0 | P18 | PMA8 | S6 | PMD41 | A9 | EVDD |
| H4 | DMD1 | P17 | PMA9 | T6 | PMD42 | A13 | EVDD |
| E2 | DMD2 | R17 | PMA 10 | S7 | PMD43 | J1 | EVDD |
| G3 | DMD3 | S18 | PMA11 | U6 | PMD44 | J18 | EVDD |
| D1 | DMD4 | P15 | PMA12 | T7 | PMD45 | N1 | EVDD |
| D2 | DMD5 | P16 | PMA13 | R8 | PMD46 | N18 | EVDD |
| F3 | DMD6 | S17 | PMA14 | S8 | PMD47 | U9 | EVDD |
| C1 | DMD7 | R16 | PMA 15 | R13 | PMS0 | U13 | EVDD |
| C2 | DMD8 | R15 | PMA16 | T15 | PMS1 | K18 | EVDD |
| F4 | DMD9 | U18 | PMA17 | U8 | PMWR | D9 | IVDD |
| E3 | DMD10 | S16 | PMA18 | S9 | PMRD | J4 | IVDD |
| D3 | DMD11 | T17 | PMA19 | S14 | PMPAGE | J15 | IVDD |
| B1 | DMD12 | 017 | PMA20 | T8 | PMTS | R9 | IVDD |
| E4 | DMD13 | R14 | PMA21 | U10 | PMACK | C10 | NC |
| B2 | DMD14 | S15 | PMA22 | A17 | $\overline{\mathrm{BG}}$ | S10 | NC |
| C3 | DMD15 | T 16 | PMA23 | A18 | $\overline{B R}$ | T10 | NC |
| A2 | DMD16 | F2 | PMDO | H16 | FLAGO | T9 | NC |
| D4 | DMD17 | F1 | PMD1 | H15 | FLAG1 | K17 | NC |
| B3 | DMD18 | J3 | PMD2 | H17 | FLAG2 | T5 | NC |
| A4 | DMD19 | H2 | PMD3 | G18 | FLAG3 | G2 | NC |
| C4 | DMD20 | H1 | PMD4 | J17 | IROO |  |  |
| B4 | DMD21 | J 2 | PMD5 | J16 | IRQ1 |  |  |
| D5 | DMD22 | K4 | PMD6 | K16 | IRQ2 |  |  |
| A6 | DMD23 | K3 | PMD7 | K15 | IRO3 |  |  |
| C5 | DMD24 | K2 | PMD8 | R10 | RESET |  |  |




## ADSP-21020

## ORDERING GUIDE

| Part Number* | Ambient Temperature <br> Range | Instruction <br> Rate (MHz) | Cycle Time <br> (ns) | Package |
| :--- | :--- | :--- | :--- | :--- |
| ADSP-21020KG-80 | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 20 | 50 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020KG-100 | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 25 | 40 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020KG-133 | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 33.3 | 30 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020BG-80 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 20 | 50 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020BG-100 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 25 | 40 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020BG-120 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 30 | 33.3 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020TG-80 | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 20 | 50 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020TG-100 | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 25 | 40 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020TG-120 | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 30 | 33.3 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020TG-80/883B | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 20 | 50 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020TG-100/883B | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 25 | 40 | 223-Lead Ceramic Pin Grid Array |
| ADSP-21020TG-120/883B | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 30 | 33.3 | 223-Lead Ceramic Pin Grid Array |

[^0]
## APPENDIX B

## Brushless DC Motor Data Sheets



## B-80X

## Mechanical Data

## KOLTMORGMy <br> Industrial Drives

## OUTLINE B.80X.X.A3




## B-802

## Performance Data







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## APPENDIX C

## Motor Drive Schematics






NOTE(S): (1) EACH NAND GATE IS $1 / 4$ पF A SN74LSOON, (2) EACH OR GATE IS
$1 / 4$ DF A SN54LS32N, AND (3) EACH AND GATE IS $1 / 4$ DF A SN54LSOBN



[^0]:    * $G=$ Ceramic Pin Grid Array.

